

Microcontrollers



Never stop thinking.

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XC164GM

16-Bit Single-Chip Microcontroller with C166SV2 Core

Microcontrollers



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16-Bit Single-Chip Microcontroller with C166SV2 Core XC166 Family

XC164GM

1 Summary of Features

- High Performance 16-bit CPU with 5-Stage Pipeline
 - 25 ns Instruction Cycle Time at 40 MHz CPU Clock (Single-Cycle Execution)
 - 1-Cycle Multiplication (16 × 16 bit), Background Division (32 / 16 bit) in 21 Cycles
 - 1-Cycle Multiply-and-Accumulate (MAC) Instructions
 - Enhanced Boolean Bit Manipulation Facilities
 - Zero-Cycle Jump Execution
 - Additional Instructions to Support HLL and Operating Systems
 - Register-Based Design with Multiple Variable Register Banks
 - Fast Context Switching Support with Two Additional Local Register Banks
 - 16 Mbytes Total Linear Address Space for Code and Data
 - 1024 Bytes On-Chip Special Function Register Area (C166 Family Compatible)
- 16-Priority-Level Interrupt System with up to 63 Sources, Sample-Rate down to 50 ns
- 8-Channel Interrupt-Driven Single-Cycle Data Transfer Facilities via Peripheral Event Controller (PEC), 24-Bit Pointers Cover Total Address Space
- Clock Generation via on-chip PLL (factors 1:0.15 ... 1:10), or via Prescaler (factors 1:1 ... 60:1)
- On-Chip Memory Modules
 - 2 Kbytes On-Chip Dual-Port RAM (DPRAM)
 - 2 Kbytes On-Chip Data SRAM (DSRAM, XC164GM-8F only)
 - 2 Kbytes On-Chip Program/Data SRAM (PSRAM)
 - 64 Kbytes (XC164GM-8F) or 32 Kbytes (XC164GM-4F) On-Chip Program Memory (Flash Memory)
- On-Chip Peripheral Modules
 - 14-Channel A/D Converter with Programmable Resolution (10-bit or 8-bit) and Conversion Time (down to 2.55 μs or 2.15 μs)
 - 16-Channel General Purpose Capture/Compare Unit (CAPCOM2)
 - Multi-Functional General Purpose Timer Unit with 5 Timers
 - Two Synchronous/Asynchronous Serial Channels (USARTs)
 - Two High-Speed-Synchronous Serial Channels
 - On-Chip TwinCAN Interface (Rev. 2.0B active) with 32 Message Objects (Full CAN/Basic CAN) on Two CAN Nodes, and Gateway Functionality
 - On-Chip Real Time Clock, Driven by the Main Oscillator
- Idle, Sleep, and Power Down Modes with Flexible Power Management
- Programmable Watchdog Timer and Oscillator Watchdog

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Summary of Features

- Up to 47 General Purpose I/O Lines, partly with Selectable Input Thresholds and Hysteresis
- On-Chip Bootstrap Loader
- On-Chip Debug Support via JTAG Interface

Ordering Information

The ordering code for Infineon microcontrollers provides an exact reference to the required product. This ordering code identifies:

- the derivative itself, i.e. its function set, the temperature range, and the supply voltage
- the package and the type of delivery.

For the available ordering codes for the XC164GM please refer to the "**Product Catalog Microcontrollers**", which summarizes all available microcontroller variants.

This document describes several derivatives of the XC164GM group. **Table 1-1** enumerates these derivatives and summarizes the differences. As this document refers to all of these derivatives, some descriptions may not apply to a specific product.

For simplicity all versions are referred to by the term **XC164GM** throughout this document.

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Summary of Features

Table 1-1 XC164GM Derivative Synopsis

Derivative ¹⁾	Temp. Range	Program Memory	On-Chip RAM	Interfaces
SAF-XC164GM-8F40F SAF-XC164GM-8F20F	-4085°C	64 Kbytes Flash	2 Kbytes DPRAM, 2 Kbytes DSRAM, 2 Kbytes PSRAM	ASC0, ASC1, SSC0, SSC1, CAN0, CAN1
SAF-XC164GM-4F40F SAF-XC164GM-4F20F	-4085°C	32 Kbytes Flash	2 Kbytes DPRAM, 2 Kbytes PSRAM	ASC0, ASC1, SSC0, SSC1, CAN0, CAN1

¹⁾ This Data Sheet is valid for devices starting with and including design step AA.



2 General Device Information

The XC164GM derivatives are high-performance members of the Infineon XC166 Family of full featured single-chip CMOS microcontrollers. These devices extend the functionality and performance of the C166 Family in terms of instructions (MAC unit), peripherals, and speed. They combine high CPU performance (up to 40 million instructions per second) with high peripheral functionality and enhanced IO-capabilities. They also provide clock generation via PLL and various on-chip memory modules such as program Flash, program RAM, and data RAM.

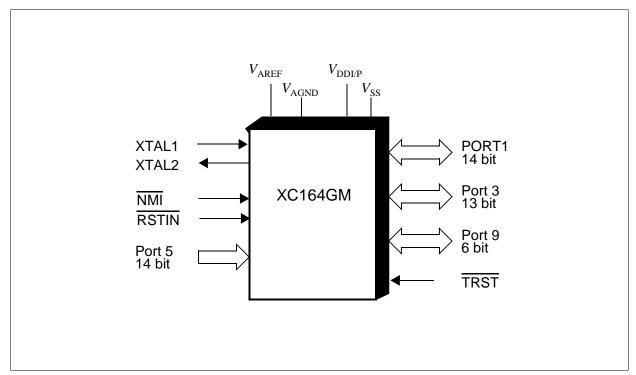


Figure 2-1 Logic Symbol

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2.1 Pin Configuration and Definition

The pins of the XC164GM are described in detail in **Table 2-1**, including all their alternate functions. **Figure 2-2** summarizes all pins in a condensed way, showing their location on the 4 sides of the package. E* marks pins to be used as alternate external interrupt inputs.

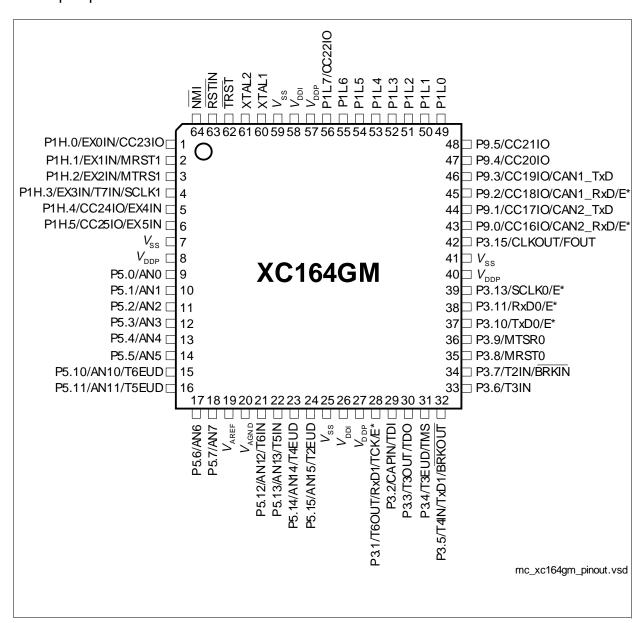


Figure 2-2 Pin Configuration (top view)



Table 2-1 Pin Definitions and Functions

Sym- bol	Pin Num.	Input Outp.	Function
RSTIN	63	I	Reset Input with Schmitt-Trigger characteristics. A low-level at this pin while the oscillator is running resets the XC164GM. A spike filter suppresses input pulses <10 ns. Input pulses >100 ns safely pass the filter. The minimum duration for a safe recognition should be 100 ns + 2 CPU clock cycles. Note: The reset duration must be sufficient to let the hardware configuration signals settle. External circuitry must guarantee low-level at the RSTIN pin at least until both power supply voltages have reached the operating range.
NMI	64	I	Non-Maskable Interrupt Input. A high to low transition at this pin causes the CPU to vector to the NMI trap routine. When the PWRDN (power down) instruction is executed, the NMI pin must be low in order to force the XC164GM into power down mode. If NMI is high, when PWRDN is executed, the part will continue to run in normal mode. If not used, pin NMI should be pulled high externally.



Table 2-1 Pin Definitions and Functions (cont'd)

Sym- bol	Pin Num.	Input Outp.	Function
Port 9	43-48	Ю	Port 9 is a 6-bit bidirectional I/O port. Each pin can be programmed for input (output driver in high-impedance state) or output (configurable as push/pull or open drain driver). The input threshold of Port 9 is selectable (standard or special). The following Port 9 pins also serve for alternate functions:
P9.0	43	I/O I I	CC16IO (CAPCOM2) CC16 Capture Inp./Compare Outp., CAN2_RxD (CAN Node 2) Receive Data Input ¹⁾ , EX5IN (Fast External Interrupt 5) Input (alternate pin B)
P9.1	44	I/O O	CC17IO (CAPCOM2) CC17 Capture Inp./Compare Outp., CAN2_TxD (CAN Node 2) Transmit Data Output,
P9.2	45	I/O I I	CC18IO (CAPCOM2) CC18 Capture Inp./Compare Outp., CAN1_RxD (CAN Node 1) Receive Data Input ¹⁾ , EX4IN (Fast External Interrupt 4) Input (alternate pin B)
P9.3	46	I/O O	CC19IO (CAPCOM2) CC19 Capture Inp./Compare Outp., CAN1_TxD (CAN Node 1) Transmit Data Output,
P9.4	47	I/O	CC20IO (CAPCOM2) CC20 Capture Inp./Compare Outp.
P9.5	48	I/O	CC21IO (CAPCOM2) CC21 Capture Inp./Compare Outp.
			Note: At the end of an external reset P9.4 and P9.5 also may input startup configuration values
Port 5	9-18, 21-24	I	Port 5 is a 14-bit input-only port. The pins of Port 5 also serve as analog input channels for the A/D converter, or they serve as timer inputs:
P5.0	9	1	AN0
P5.1	10	1	AN1
P5.2	11	1	AN2
P5.3	12	I	AN3
P5.4	13	I	AN4
P5.5	14	I	AN5
P5.10	15	I	AN10 (T6EUD) GPT2 Timer T6 Ext. Up/Down Ctrl. Inp.
P5.11	16	I	AN11 (T5EUD) GPT2 Timer T5 Ext. Up/Down Ctrl. Inp.
P5.6	17		AN6
P5.7	18	I	AN7
P5.12	21		AN12 (T6IN) GPT2 Timer T6 Count/Gate Input
P5.13	22	I	AN13 (T5IN) GPT2 Timer T5 Count/Gate Input
P5.14	23		AN14 (T4EUD) GPT1 Timer T4 Ext. Up/Down Ctrl. Inp.
P5.15	24	I	AN15 (T2EUD) GPT1 Timer T2 Ext. Up/Down Ctrl. Inp.



 Table 2-1
 Pin Definitions and Functions (cont'd)

Sym- bol	Pin Num.	Input Outp.	Function
TRST	62	I	Test-System Reset Input. A high level at this pin activates the XC164GM's debug system. For normal system operation, pin TRST should be held low.
Port 3	28-39, 42	Ю	Port 3 is a 13-bit bidirectional I/O port. Each pin can be programmed for input (output driver in high-impedance state) or output (configurable as push/pull or open drain driver). The input threshold of Port 3 is selectable (standard or special). The following Port 3 pins also serve for alternate functions:
P3.1	28	O I/O I	T6OUT [GPT2] Timer T6 Toggle Latch Output, RxD1 [ASC1] Data Input (Async.) or Inp./Outp. (Sync.), EX1IN [Fast External Interrupt 1] Input (alternate pin A), TCK [Debug System] JTAG Clock Input
P3.2	29	I	CAPIN [GPT2] Register CAPREL Capture Input, TDI [Debug System] JTAG Data In
P3.3	30	0	T3OUT [GPT1] Timer T3 Toggle Latch Output, TDO [Debug System] JTAG Data Out
P3.4	31	1	T3EUD [GPT1] Timer T3 External Up/Down Control Input, TMS [Debug System] JTAG Test Mode Selection
P3.5	32	I 0 0	T4IN [GPT1] Timer T4 Count/Gate/Reload/Capture Inp TxD1 [ASC0] Clock/Data Output (Async./Sync.), BRKOUT [Debug System] Break Out
P3.6	33	ı	T3IN [GPT1] Timer T3 Count/Gate Input
P3.7	34	1	T2IN [GPT1] Timer T2 Count/Gate/Reload/Capture Inp BRKIN [Debug System] Break In
P3.8	35	I/O	MRST0 [SSC0] Master-Receive/Slave-Transmit In/Out.
P3.9	36	I/O	MTSR0 [SSC0] Master-Transmit/Slave-Receive Out/In.
P3.10	37	0	TxD0 [ASC0] Clock/Data Output (Async./Sync.), EX2IN [Fast External Interrupt 2] Input (alternate pin B)
P3.11	38	I/O I	RxD0 [ASC0] Data Input (Async.) or Inp./Outp. (Sync.), EX2IN [Fast External Interrupt 2] Input (alternate pin A)
P3.13	39	I/O I	SCLK0 [SSC0] Master Clock Output / Slave Clock Input., EX3IN [Fast External Interrupt 3] Input (alternate pin A)
P3.15	42	0	CLKOUT System Clock Output (= CPU Clock), FOUT Programmable Frequency Output



 Table 2-1
 Pin Definitions and Functions (cont'd)

Sym- bol	Pin Num.	Input Outp.	Function
PORT1	1-6, 49-56	Ю	PORT1 consists of one 8-bit and one 6-bit bidirectional I/O port P1L and P1H. Each pin can be programmed for input (output driver in high-impedance state) or output. The following PORT1 pins also serve for alt. functions:
P1L.7	56	I/O	CC22IO [CAPCOM2] CC22 Capture Inp./Compare Outp.
P1H.0	1	I I/O	EX0IN [Fast External Interrupt 0] Input (default pin), CC23IO [CAPCOM2] CC23 Capture Inp./Compare Outp.
P1H.1	2	I I/O	EX1IN [Fast External Interrupt 1] Input (default pin), MRST1 [SSC1] Master-Receive/Slave-Transmit In/Out.
P1H.2	3	I I/O	EX2IN [Fast External Interrupt 2] Input (default pin), MTSR1 [SSC1] Master-Transmit/Slave-Receive Out/Inp.
P1H.3	3	 /O 	T7IN [CAPCOM2] Timer T7 Count Input, SCLK1 [SSC1] Master Clock Output / Slave Clock Input, EX3IN [Fast External Interrupt 3] Input (default pin),
P1H.4	5	I/O I	CC24IO [CAPCOM2] CC24 Capture Inp./Compare Outp., EX4IN [Fast External Interrupt 4] Input (default pin)
P1H.5	6	I/O I	CC25IO [CAPCOM2] CC25 Capture Inp./Compare Outp., EX5IN [Fast External Interrupt 5] Input (default pin)
			Note: At the end of an external reset P1H.4 and P1H.5 also may input startup configuration values
XTAL2 XTAL1	61 60	OI	XTAL2: Output of the oscillator amplifier circuit XTAL1: Input to the oscillator amplifier and input to the internal clock generator To clock the device from an external source, drive XTAL1, while leaving XTAL2 unconnected. Minimum and maximum high/low and rise/fall times specified in the AC Characteristics must be observed.
V_{AREF}	19	-	Reference voltage for the A/D converter.
V_{AGND}	20	-	Reference ground for the A/D converter.
V_{DDI}	26, 58	-	Digital Core Supply Voltage (On-Chip Modules): +2.5 V during normal operation and idle mode. Please refer to the Operating Condition Parameters



Table 2-1 Pin Definitions and Functions (cont'd)

Sym- bol	Pin Num.	Input Outp.	Function
$\overline{V_{DDP}}$	8, 27, 40,57	-	Digital Pad Supply Voltage (Pin Output Drivers): +5 V during normal operation and idle mode. Please refer to the Operating Condition Parameters
$\overline{V_{ t SS}}$	7, 25, 41, 59	-	Digital Ground. Connect decoupling capacitors to adjacent $V_{\rm DD}/V_{\rm SS}$ pin pairs as close as possible to the pins. All $V_{\rm SS}$ pins must be connected to the ground-line or ground-plane.

¹⁾ The CAN interface lines are assigned to port P9 under software control.



3 Functional Description

The architecture of the XC164GM combines advantages of RISC, CISC, and DSP processors with an advanced peripheral subsystem in a very well-balanced way. In addition, the on-chip memory blocks allow the design of compact systems-on-silicon with maximum performance (computing, control, communication).

The on-chip memory blocks (program code-memory and SRAM, dual-port RAM, data SRAM) and the set of generic peripherals are connected to the CPU via separate buses. Another bus, the LXBus, connects additional on-chip resources (see **Figure 3-1**).

This bus structure enhances the overall system performance by enabling the concurrent operation of several subsystems of the XC164GM.

The following block diagram gives an overview of the different on-chip components and of the advanced, high bandwidth internal bus structure of the XC164GM.

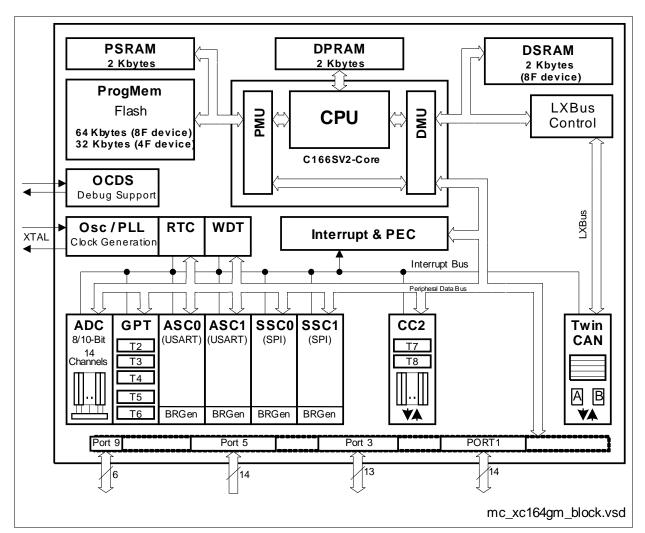


Figure 3-1 Block Diagram



3.1 Memory Subsystem and Organization

The memory space of the XC164GM is configured in a von Neumann architecture, which means that all internal and external resources, such as code memory, data memory, registers and I/O ports, are organized within the same linear address space. This common memory space includes 16 Mbytes and is arranged as 256 segments of 64 Kbytes each, where each segment consists of four data pages of 16 Kbytes each. The entire memory space can be accessed byte wise or word wise. Portions of the on-chip DPRAM and the register spaces (E/SFR) have additionally been made directly bit addressable.

The internal data memory areas and the Special Function Register areas (SFR and ESFR) are mapped into segment 0, the system segment.

The Program Management Unit (PMU) handles all code fetches and, therefore, controls accesses to the program memories, such as Flash memory and PSRAM.

The Data Management Unit (DMU) handles all data transfers and, therefore, controls accesses to the DSRAM and the on-chip peripherals.

Both units (PMU and DMU) are connected via the high-speed system bus to exchange data. This is required if operands are read from program memory, code or data is written to the PSRAM, or data is read from or written to peripherals on the LXBus (such as TwinCAN). The system bus allows concurrent two-way communication for maximum transfer performance.

64 or 32 Kbytes of on-chip Flash memory store code or constant data. The on-chip Flash memory is organized as four 8-Kbyte sectors and one 32-Kbyte (XC164GM-8F only) sector. Each sector can be separately write protected¹⁾, erased and programmed (in blocks of 128 Bytes). The complete Flash area can be read-protected. A password sequence temporarily unlocks protected areas. The Flash module combines very fast 64-bit one-cycle read accesses with protected and efficient writing algorithms for programming and erasing. Thus, program execution out of the internal Flash results in maximum performance. Dynamic error correction provides extremely high read data security for all read accesses.

Programming typically takes 2 ms per 128-byte block (5 ms max.), erasing a sector typically takes 200 ms (500 ms max.).

- **2 Kbytes of on-chip Program SRAM (PSRAM)** are provided to store user code or data. The PSRAM is accessed via the PMU and is therefore optimized for code fetches.
- **2 Kbytes of on-chip Data SRAM (DSRAM)** are provided as a storage for general user data. The DSRAM is accessed via the DMU and is therefore optimized for data accesses. DSRAM is only available in the XC164GM-8F derivatives.
- **2 Kbytes of on-chip Dual-Port RAM (DPRAM)** are provided as a storage for user defined variables, for the system stack, general purpose register banks. A register bank

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¹⁾ Each two 8-Kbyte sectors are combined for write-protection purposes.



can consist of up to 16 word wide (R0 to R15) and/or byte wide (RL0, RH0, ..., RL7, RH7) so-called General Purpose Registers (GPRs).

The upper 256 bytes of the DPRAM are directly bit addressable. When used by a GPR, any location in the DPRAM is bit addressable.

1024 bytes (2 \times **512 bytes)** of the address space are reserved for the Special Function Register areas (SFR space and ESFR space). SFRs are word wide registers which are used for controlling and monitoring functions of the different on-chip units. Unused SFR addresses are reserved for future members of the XC166 Family. Therefore, they should either not be accessed, or written with zeros, to ensure upward compatibility.

Table 3-1 XC164GM Memory Map

Address Area	Start Loc.	End Loc.	Area Size ¹⁾	Notes
Flash register space	FF'F000 _H	FF'FFFF _H	4 Kbytes	2)
Reserved (Acc. trap)	F8'0000 _H	FF'FFFF _H	508 Kbytes	
Reserved for PSRAM	E0'0800 _H	F7'FFFF _H	< 1.5 Mbytes	Minus PSRAM
Program SRAM	E0'0000 _H	E0'07FF _H	2 Kbytes	
Reserved for pr. mem.	C1'0000 _H	DF'FFFF _H	< 2 Mbytes	Minus Flash
Program Flash	C0'0000 _H	C0'FFFF _H	64 Kbytes	XC164GM-8F
	C0'0000 _H	C0'7FFF _H	32 Kbytes	XC164GM-4F
Reserved	20'0800 _H	BF'FFFF _H	< 10 Mbytes	Minus TwinCAN
TwinCAN registers	20'0000 _H	20'07FF _H	2 Kbytes	Accessed via EBC
Reserved	01'0000 _H	1F'FFFF _H	< 2 Mbytes	Minus segment 0
SFR area	00'FE00 _H	00'FFFF _H	0.5 Kbyte	-
Dual-Port RAM	00'F600 _H	00'FDFF _H	2 Kbytes	-
Reserved for DPRAM	00'F200 _H	00'F5FF _H	1 Kbyte	-
ESFR area	00'F000 _H	00'F1FF _H	0.5 Kbyte	-
XSFR area	00'E000 _H	00'EFFF _H	4 Kbytes	-
Reserved	00'C800 _H	00'DFFF _H	6 Kbytes	-
Data SRAM	00'C000 _H	00'C7FF _H	2 Kbytes	XC164GM-8F only
Reserved for DSRAM	00'8000 _H	00'BFFF _H	16 Kbytes	_
Reserved	00'0000 _H	00'7FFF _H	32 Kbytes	_

¹⁾ The areas marked with "<" are slightly smaller than indicated, see column "Notes".

²⁾ Not defined register locations return a trap code (1E9B_H).



3.2 Central Processing Unit (CPU)

The main core of the CPU consists of a 5-stage execution pipeline with a 2-stage instruction-fetch pipeline, a 16-bit arithmetic and logic unit (ALU), a 32-bit/40-bit multiply and accumulate unit (MAC), a register-file providing three register banks, and dedicated SFRs. The ALU features a multiply and divide unit, a bit-mask generator, and a barrel shifter.

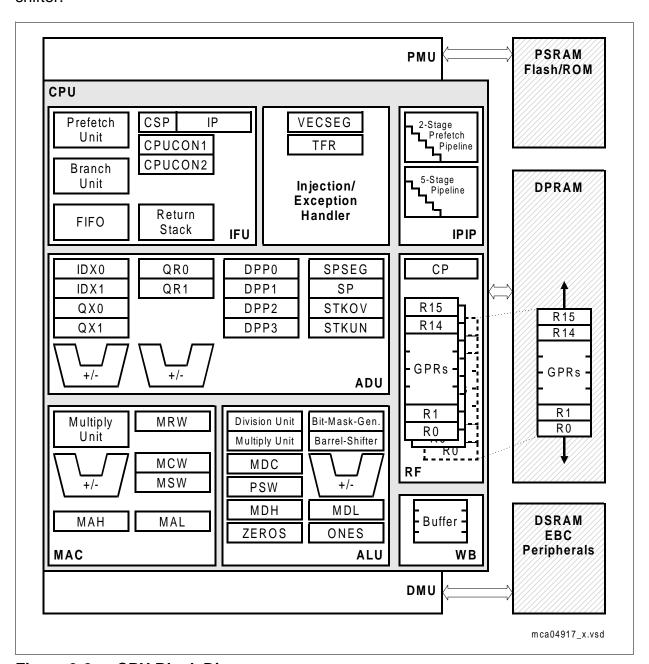


Figure 3-2 CPU Block Diagram

Based on these hardware provisions, most of the XC164GM's instructions can be executed in just one machine cycle which requires 25 ns at 40 MHz CPU clock. For



example, shift and rotate instructions are always processed during one machine cycle independent of the number of bits to be shifted. Also multiplication and most MAC instructions execute in one single cycle. All multiple-cycle instructions have been optimized so that they can be executed very fast as well: for example, a 32-/16-bit division is started within 4 cycles, while the remaining 15 cycles are executed in the background. Another pipeline optimization, the branch target prediction, allows eliminating the execution time of branch instructions if the prediction was correct.

The CPU has a register context consisting of up to three register banks with 16 word wide GPRs each at its disposal. One of these register banks is physically allocated within the on-chip DPRAM area. A Context Pointer (CP) register determines the base address of the active register bank to be accessed by the CPU at any time. The number of register banks is only restricted by the available internal RAM space. For easy parameter passing, a register bank may overlap others.

A system stack of up to 32 Kwords is provided as a storage for temporary data. The system stack can be allocated to any location within the address space (preferably in the on-chip RAM area), and it is accessed by the CPU via the stack pointer (SP) register. Two separate SFRs, STKOV and STKUN, are implicitly compared against the stack pointer value upon each stack access for the detection of a stack overflow or underflow.

The high performance offered by the hardware implementation of the CPU can efficiently be utilized by a programmer via the highly efficient XC164GM instruction set which includes the following instruction classes:

- Standard Arithmetic Instructions
- DSP-Oriented Arithmetic Instructions
- Logical Instructions
- Boolean Bit Manipulation Instructions
- Compare and Loop Control Instructions
- Shift and Rotate Instructions
- Prioritize Instruction
- Data Movement Instructions
- System Stack Instructions
- Jump and Call Instructions
- Return Instructions
- System Control Instructions
- Miscellaneous Instructions

The basic instruction length is either 2 or 4 bytes. Possible operand types are bits, bytes and words. A variety of direct, indirect or immediate addressing modes are provided to specify the required operands.



3.3 Interrupt System

With an interrupt response time of typically 8 CPU clocks (in case of internal program execution), the XC164GM is capable of reacting very fast to the occurrence of non-deterministic events.

The architecture of the XC164GM supports several mechanisms for fast and flexible response to service requests that can be generated from various sources internal or external to the microcontroller. Any of these interrupt requests can be programmed to being serviced by the Interrupt Controller or by the Peripheral Event Controller (PEC).

In contrast to a standard interrupt service where the current program execution is suspended and a branch to the interrupt vector table is performed, just one cycle is 'stolen' from the current CPU activity to perform a PEC service. A PEC service implies a single byte or word data transfer between any two memory locations with an additional increment of either the PEC source, or the destination pointer, or both. An individual PEC transfer counter is implicitly decremented for each PEC service except when performing in the continuous transfer mode. When this counter reaches zero, a standard interrupt is performed to the corresponding source related vector location. PEC services are very well suited, for example, for supporting the transmission or reception of blocks of data. The XC164GM has 8 PEC channels each of which offers such fast interrupt-driven data transfer capabilities.

A separate control register which contains an interrupt request flag, an interrupt enable flag and an interrupt priority bit field exists for each of the possible interrupt nodes. Via its related register, each node can be programmed to one of sixteen interrupt priority levels. Once having been accepted by the CPU, an interrupt service can only be interrupted by a higher prioritized service request. For the standard interrupt processing, each of the possible interrupt nodes has a dedicated vector location.

Fast external interrupt inputs are provided to service external interrupts with high precision requirements. These fast interrupt inputs feature programmable edge detection (rising edge, falling edge, or both edges).

Software interrupts are supported by means of the 'TRAP' instruction in combination with an individual trap (interrupt) number.

Table 3-2 shows all of the possible XC164GM interrupt sources and the corresponding hardware-related interrupt flags, vectors, vector locations and trap (interrupt) numbers.

Note: Interrupt nodes which are not assigned to peripherals (unassigned nodes), may be used to generate software controlled interrupt requests by setting the respective interrupt request bit (xIR).

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Table 3-2 XC164GM Interrupt Nodes

Source of Interrupt or PEC Service Request	Control Register	Vector Location ¹⁾	Trap Number
EXOIN	CC1_CC8IC	xx'0060 _H	18 _H / 24 _D
EX1IN	CC1_CC9IC	xx'0064 _H	19 _H / 25 _D
EX2IN	CC1_CC10IC	xx'0068 _H	1A _H / 26 _D
EX3IN	CC1_CC11IC	xx'006C _H	1B _H / 27 _D
EX4IN	CC1_CC12IC	xx'0070 _H	1C _H / 28 _D
EX5IN	CC1_CC13IC	xx'0074 _H	1D _H / 29 _D
CAPCOM Register 16	CC2_CC16IC	xx'00C0 _H	30 _H / 48 _D
CAPCOM Register 17	CC2_CC17IC	xx'00C4 _H	31 _H / 49 _D
CAPCOM Register 18	CC2_CC18IC	xx'00C8 _H	32 _H / 50 _D
CAPCOM Register 19	CC2_CC19IC	xx'00CC _H	33 _H / 51 _D
CAPCOM Register 20	CC2_CC20IC	xx'00D0 _H	34 _H / 52 _D
CAPCOM Register 21	CC2_CC21IC	xx'00D4 _H	35 _H / 53 _D
CAPCOM Register 22	CC2_CC22IC	xx'00D8 _H	36 _H / 54 _D
CAPCOM Register 23	CC2_CC23IC	xx'00DC _H	37 _H / 55 _D
CAPCOM Register 24	CC2_CC24IC	xx'00E0 _H	38 _H / 56 _D
CAPCOM Register 25	CC2_CC25IC	xx'00E4 _H	39 _H / 57 _D
CAPCOM Register 26	CC2_CC26IC	xx'00E8 _H	3A _H / 58 _D
CAPCOM Register 27	CC2_CC27IC	xx'00EC _H	3B _H / 59 _D
CAPCOM Register 28	CC2_CC28IC	xx'00F0 _H	3C _H / 60 _D
CAPCOM Register 29	CC2_CC29IC	xx'0110 _H	44 _H / 68 _D
CAPCOM Register 30	CC2_CC30IC	xx'0114 _H	45 _H / 69 _D
CAPCOM Register 31	CC2_CC31IC	xx'0118 _H	46 _H / 70 _D
CAPCOM Timer 7	CC2_T7IC	xx'00F4 _H	3D _H / 61 _D
CAPCOM Timer 8	CC2_T8IC	xx'00F8 _H	3E _H / 62 _D
GPT1 Timer 2	GPT12E_T2IC	xx'0088 _H	22 _H / 34 _D
GPT1 Timer 3	GPT12E_T3IC	xx'008C _H	23 _H / 35 _D
GPT1 Timer 4	GPT12E_T4IC	xx'0090 _H	24 _H / 36 _D
GPT2 Timer 5	GPT12E_T5IC	xx'0094 _H	25 _H / 37 _D
GPT2 Timer 6	GPT12E_T6IC	xx'0098 _H	26 _H / 38 _D



Table 3-2 XC164GM Interrupt Nodes (cont'd)

Source of Interrupt or PEC Service Request	Control Register	Vector Location ¹⁾	Trap Number
GPT2 CAPREL Register	GPT12E_CRIC	xx'009C _H	27 _H / 39 _D
A/D Conversion Complete	ADC_CIC	xx'00A0 _H	28 _H / 40 _D
A/D Overrun Error	ADC_EIC	xx'00A4 _H	29 _H / 41 _D
ASC0 Transmit	ASC0_TIC	xx'00A8 _H	2A _H / 42 _D
ASC0 Transmit Buffer	ASC0_TBIC	xx'011C _H	47 _H / 71 _D
ASC0 Receive	ASC0_RIC	xx'00AC _H	2B _H / 43 _D
ASC0 Error	ASC0_EIC	xx'00B0 _H	2C _H / 44 _D
ASC0 Autobaud	ASC0_ABIC	xx'017C _H	5F _H / 95 _D
SSC0 Transmit	SSC0_TIC	xx'00B4 _H	2D _H / 45 _D
SSC0 Receive	SSC0_RIC	xx'00B8 _H	2E _H / 46 _D
SSC0 Error	SSC0_EIC	xx'00BC _H	2F _H / 47 _D
PLL/OWD	PLLIC	xx'010C _H	43 _H / 67 _D
ASC1 Transmit	ASC1_TIC	xx'0120 _H	48 _H / 72 _D
ASC1 Transmit Buffer	ASC1_TBIC	xx'0178 _H	5E _H / 94 _D
ASC1 Receive	ASC1_RIC	xx'0124 _H	49 _H / 73 _D
ASC1 Error	ASC1_EIC	xx'0128 _H	4A _H / 74 _D
ASC1 Autobaud	ASC1_ABIC	xx'0108 _H	42 _H / 66 _D
End of PEC Subchannel	EOPIC	xx'0130 _H	4C _H / 76 _D
SSC1 Transmit	SSC1_TIC	xx'0144 _H	51 _H / 81 _D
SSC1 Receive	SSC1_RIC	xx'0148 _H	52 _H / 82 _D
SSC1 Error	SSC1_EIC	xx'014C _H	53 _H / 83 _D
CAN0	CAN_0IC	xx'0150 _H	54 _H / 84 _D
CAN1	CAN_1IC	xx'0154 _H	55 _H / 85 _D
CAN2	CAN_2IC	xx'0158 _H	56 _H / 86 _D
CAN3	CAN_3IC	xx'015C _H	57 _H / 87 _D
CAN4	CAN_4IC	xx'0164 _H	59 _H / 89 _D
CAN5	CAN_5IC	xx'0168 _H	5A _H / 90 _D
CAN6	CAN_6IC	xx'016C _H	5B _H / 91 _D
CAN7	CAN_7IC	xx'0170 _H	5C _H / 92 _D
RTC	RTC_IC	xx'0174 _H	5D _H / 93 _D



Table 3-2 XC164GM Interrupt Nodes (cont'd)

Source of Interrupt or PEC Service Request	Control Register	Vector Location ¹⁾	Trap Number
Unassigned node	_	xx'0040 _H	10 _H / 16 _D
Unassigned node	_	xx'0044 _H	11 _H / 17 _D
Unassigned node	_	xx'0048 _H	12 _H / 18 _D
Unassigned node	_	xx'004C _H	13 _H / 19 _D
Unassigned node	_	xx'0050 _H	14 _H / 20 _D
Unassigned node	_	xx'0054 _H	15 _H / 21 _D
Unassigned node	_	xx'0058 _H	16 _H / 22 _D
Unassigned node	_	xx'005C _H	17 _H / 23 _D
Unassigned node	_	xx'0078 _H	1E _H / 30 _D
Unassigned node	_	xx'007C _H	1F _H / 31 _D
Unassigned node	_	xx'0080 _H	20 _H / 32 _D
Unassigned node	_	xx'0084 _H	21 _H / 33 _D
Unassigned node	_	xx'00FC _H	3F _H / 63 _D
Unassigned node	_	xx'0100 _H	40 _H / 64 _D
Unassigned node	_	xx'0104 _H	41 _H / 65 _D
Unassigned node	_	xx'012C _H	4B _H / 75 _D
Unassigned node	_	xx'0134 _H	4D _H / 77 _D
Unassigned node	_	xx'0138 _H	4E _H / 78 _D
Unassigned node	_	xx'013C _H	4F _H / 79 _D
Unassigned node	_	xx'0140 _H	50 _H / 80 _D
Unassigned node	_	xx'0160 _H	58 _H / 88 _D

Register VECSEG defines the segment where the vector table is located to.
 Bitfield VECSC in register CPUCON1 defines the distance between two adjacent vectors. This table represents the default setting, with a distance of 4 (two words) between two vectors.



The XC164GM also provides an excellent mechanism to identify and to process exceptions or error conditions that arise during run-time, so-called 'Hardware Traps'. Hardware traps cause immediate non-maskable system reaction which is similar to a standard interrupt service (branching to a dedicated vector table location). The occurrence of a hardware trap is additionally signified by an individual bit in the trap flag register (TFR). Except when another higher prioritized trap service is in progress, a hardware trap will interrupt any actual program execution. In turn, hardware trap services can normally not be interrupted by standard or PEC interrupts.

Table 3-3 shows all of the possible exceptions or error conditions that can arise during run-time:

Table 3-3 Hardware Trap Summary

Exception Condition	Trap Flag	Trap Vector	Vector Location ¹⁾	Trap Number	Trap Priority
Reset Functions: Hardware Reset Software Reset W-dog Timer Overflow	-	RESET RESET RESET	xx'0000 _H xx'0000 _H	00 _H 00 _H 00 _H	
Class A Hardware Traps: Non-Maskable InterruptStack OverflowStack UnderflowSoftware Break	NMI STKOF STKUF SOFTBRK	NMITRAP STOTRAP STUTRAP SBRKTRAP	xx'0008 _H xx'0010 _H xx'0018 _H xx'0020 _H	02 _H 04 _H 06 _H 08 _H	
Class B Hardware Traps: Undefined Opcode PMI Access Error Protected Instruction Fault Illegal Word Operand Access	UNDOPC PACER PRTFLT ILLOPA	BTRAP BTRAP BTRAP BTRAP	xx'0028 _H xx'0028 _H xx'0028 _H xx'0028 _H	0A _H 0A _H 0A _H	
Reserved	_	-	[2C _H - 3C _H]	[0B _H - 0F _H]	_
Software Traps TRAP Instruction	_	_	Any [xx'0000 _H - xx'01FC _H] in steps of 4 _H	Any [00 _H - 7F _H]	Current CPU Priority

Register VECSEG defines the segment where the vector table is located to.
 Bitfield VECSC in register CPUCON1 defines the distance between two adjacent vectors. This table represents the default setting, with a distance of 4 (two words) between two vectors.

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3.4 On-Chip Debug Support (OCDS)

The On-Chip Debug Support system provides a broad range of debug and emulation features built into the XC164GM. The user software running on the XC164GM can thus be debugged within the target system environment.

The OCDS is controlled by an external debugging device via the debug interface, consisting of the IEEE-1149-conforming JTAG port and a break interface. The debugger controls the OCDS via a set of dedicated registers accessible via the JTAG interface. Additionally, the OCDS system can be controlled by the CPU, e.g. by a monitor program. An injection interface allows the execution of OCDS-generated instructions by the CPU.

Multiple breakpoints can be triggered by on-chip hardware, by software, or by an external trigger input. Single stepping is supported as well as the injection of arbitrary instructions and read/write access to the complete internal address space. A breakpoint trigger can be answered with a CPU-halt, a monitor call, a data transfer, or/and the activation of an external signal.

Tracing data can be obtained via the JTAG interface.

The debug interface uses a set of 6 interface signals (4 JTAG lines, 2 break lines) to communicate with external circuitry. These interface signals are realized as alternate functions on Port 3 pins.

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3.5 Capture/Compare Unit (CAPCOM2)

The CAPCOM unit supports generation and control of timing sequences on up to 16 channels with a maximum resolution of 1 system clock cycle (8 cycles in staggered mode). The CAPCOM unit is typically used to handle high speed I/O tasks such as pulse and waveform generation, pulse width modulation (PWM), Digital to Analog (D/A) conversion, software timing, or time recording relative to external events.

Two 16-bit timers (T7/T8) with reload registers provide two independent time bases for the capture/compare register array.

The input clock for the timers is programmable to several prescaled values of the internal system clock, or may be derived from an overflow/underflow of timer T6 in module GPT2. This provides a wide range of variation for the timer period and resolution and allows precise adjustments to the application specific requirements. In addition, an external count input for CAPCOM timer T7 allows event scheduling for the capture/compare registers relative to external events.

The capture/compare register array contains 16 dual purpose capture/compare registers, each of which may be individually allocated to either CAPCOM timer (T7 or T8, respectively), and programmed for capture or compare function.

10 registers of the CAPCOM2 module have each one port pin associated with it which serves as an input pin for triggering the capture function, or as an output pin to indicate the occurrence of a compare event.

Table 3-4 Compare Modes (CAPCOM2)

Compare Modes	Function		
Mode 0	Interrupt-only compare mode; Several compare interrupts per timer period are possible		
Mode 1	Pin toggles on each compare match; Several compare events per timer period are possible		
Mode 2	Interrupt-only compare mode; Only one compare interrupt per timer period is generated		
Mode 3	Pin set '1' on match; pin reset '0' on compare timer overflow; Only one compare event per timer period is generated		
Double Register Mode	Two registers operate on one pin; Pin toggles on each compare match; Several compare events per timer period are possible		
Single Event Mode	Generates single edges or pulses; Can be used with any compare mode		

When a capture/compare register has been selected for capture mode, the current contents of the allocated timer will be latched ('captured') into the capture/compare

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register in response to an external event at the port pin which is associated with this register. In addition, a specific interrupt request for this capture/compare register is generated. Either a positive, a negative, or both a positive and a negative external signal transition at the pin can be selected as the triggering event.

The contents of all registers which have been selected for one of the five compare modes are continuously compared with the contents of the allocated timers.

When a match occurs between the timer value and the value in a capture/compare register, specific actions will be taken based on the selected compare mode.



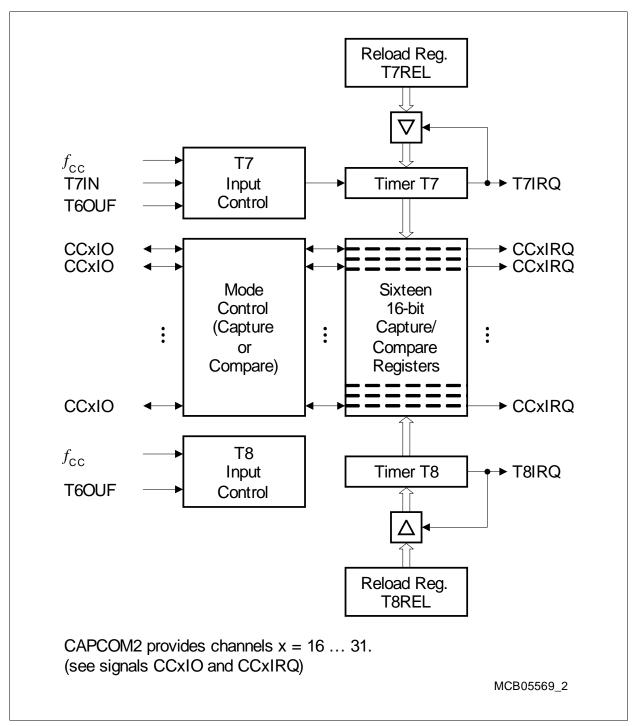


Figure 3-3 CAPCOM2 Unit Block Diagram



3.6 General Purpose Timer (GPT12E) Unit

The GPT12E unit represents a very flexible multifunctional timer/counter structure which may be used for many different time related tasks such as event timing and counting, pulse width and duty cycle measurements, pulse generation, or pulse multiplication.

The GPT12E unit incorporates five 16-bit timers which are organized in two separate modules, GPT1 and GPT2. Each timer in each module may operate independently in a number of different modes, or may be concatenated with another timer of the same module.

Each of the three timers T2, T3, T4 of **module GPT1** can be configured individually for one of four basic modes of operation, which are Timer, Gated Timer, Counter, and Incremental Interface Mode. In Timer Mode, the input clock for a timer is derived from the system clock, divided by a programmable prescaler, while Counter Mode allows a timer to be clocked in reference to external events.

Pulse width or duty cycle measurement is supported in Gated Timer Mode, where the operation of a timer is controlled by the 'gate' level on an external input pin. For these purposes, each timer has one associated port pin (TxIN) which serves as gate or clock input. The maximum resolution of the timers in module GPT1 is 4 system clock cycles.

The count direction (up/down) for each timer is programmable by software or may additionally be altered dynamically by an external signal on a port pin (TxEUD) to facilitate e.g. position tracking.

In Incremental Interface Mode the GPT1 timers (T2, T3, T4) can be directly connected to the incremental position sensor signals A and B via their respective inputs TxIN and TxEUD. Direction and count signals are internally derived from these two input signals, so the contents of the respective timer Tx corresponds to the sensor position. The third position sensor signal TOP0 can be connected to an interrupt input.

Timer T3 has an output toggle latch (T3OTL) which changes its state on each timer overflow/underflow. The state of this latch may be output on pin T3OUT e.g. for time out monitoring of external hardware components. It may also be used internally to clock timers T2 and T4 for measuring long time periods with high resolution.

In addition to their basic operating modes, timers T2 and T4 may be configured as reload or capture registers for timer T3. When used as capture or reload registers, timers T2 and T4 are stopped. The contents of timer T3 is captured into T2 or T4 in response to a signal at their associated input pins (TxIN). Timer T3 is reloaded with the contents of T2 or T4 triggered either by an external signal or by a selectable state transition of its toggle latch T3OTL. When both T2 and T4 are configured to alternately reload T3 on opposite state transitions of T3OTL with the low and high times of a PWM signal, this signal can be constantly generated without software intervention.

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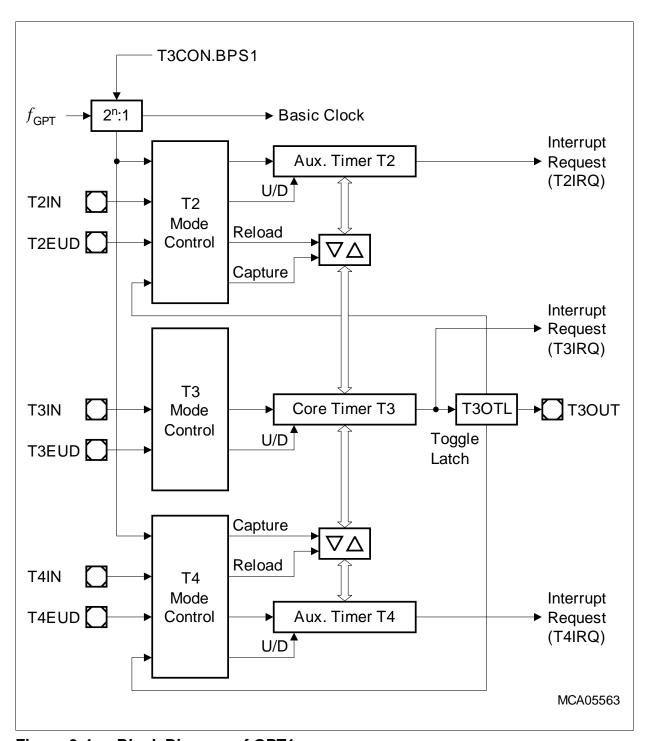


Figure 3-4 Block Diagram of GPT1

With its maximum resolution of 2 system clock cycles, the **GPT2 module** provides precise event control and time measurement. It includes two timers (T5, T6) and a capture/reload register (CAPREL). Both timers can be clocked with an input clock which is derived from the CPU clock via a programmable prescaler or with external signals. The



count direction (up/down) for each timer is programmable by software or may additionally be altered dynamically by an external signal on a port pin (TxEUD). Concatenation of the timers is supported via the output toggle latch (T6OTL) of timer T6, which changes its state on each timer overflow/underflow.

The state of this latch may be used to clock timer T5, and/or it may be output on pin T6OUT. The overflows/underflows of timer T6 can additionally be used to clock the CAPCOM2 timers, and to cause a reload from the CAPREL register.

The CAPREL register may capture the contents of timer T5 based on an external signal transition on the corresponding port pin (CAPIN), and timer T5 may optionally be cleared after the capture procedure. This allows the XC164GM to measure absolute time differences or to perform pulse multiplication without software overhead.

The capture trigger (timer T5 to CAPREL) may also be generated upon transitions of GPT1 timer T3's inputs T3IN and/or T3EUD. This is especially advantageous when T3 operates in Incremental Interface Mode.

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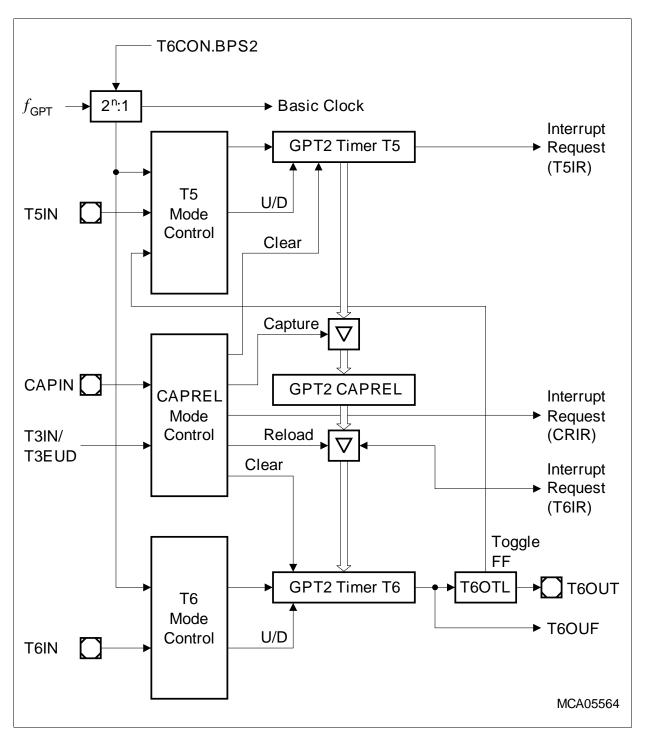


Figure 3-5 Block Diagram of GPT2



3.7 Real Time Clock

The Real Time Clock (RTC) module of the XC164GM is directly clocked via a separate clock driver with the prescaled on-chip main oscillator frequency ($f_{\rm RTC} = f_{\rm OSCm}/32$). It is therefore independent from the selected clock generation mode of the XC164GM.

The RTC basically consists of a chain of divider blocks:

- A selectable 8:1 divider (on off)
- The reloadable 16-bit timer T14
- The 32-bit RTC timer block (accessible via registers RTCH and RTCL), made of:
 - a reloadable 10-bit timer
 - a reloadable 6-bit timer
 - a reloadable 6-bit timer
 - a reloadable 10-bit timer

All timers count up. Each timer can generate an interrupt request. All requests are combined to a common node request.

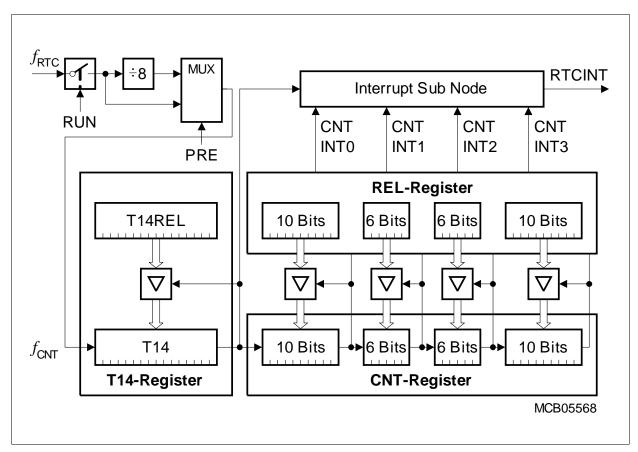


Figure 3-6 RTC Block Diagram

Note: The registers associated with the RTC are not affected by a reset in order to maintain the correct system time even when intermediate resets are executed.

The RTC module can be used for different purposes:

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- System clock to determine the current time and date, optionally during idle mode, sleep mode, and power down mode
- Cyclic time based interrupt, to provide a system time tick independent of CPU frequency and other resources, e.g. to wake up regularly from idle mode
- 48-bit timer for long term measurements (maximum timespan is > 100 years)
- Alarm interrupt for wake-up on a defined time

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3.8 A/D Converter

For analog signal measurement, a 10-bit A/D converter with 14 multiplexed input channels and a sample and hold circuit has been integrated on-chip. It uses the method of successive approximation. The sample time (for loading the capacitors) and the conversion time is programmable (in two modes) and can thus be adjusted to the external circuitry. The A/D converter can also operate in 8-bit conversion mode, where the conversion time is further reduced.

Overrun error detection/protection is provided for the conversion result register (ADDAT): either an interrupt request will be generated when the result of a previous conversion has not been read from the result register at the time the next conversion is complete, or the next conversion is suspended in such a case until the previous result has been read.

For applications which require less analog input channels, the remaining channel inputs can be used as digital input port pins.

The A/D converter of the XC164GM supports four different conversion modes. In the standard Single Channel conversion mode, the analog level on a specified channel is sampled once and converted to a digital result. In the Single Channel Continuous mode, the analog level on a specified channel is repeatedly sampled and converted without software intervention. In the Auto Scan mode, the analog levels on a prespecified number of channels are sequentially sampled and converted. In the Auto Scan Continuous mode, the prespecified channels are repeatedly sampled and converted. In addition, the conversion of a specific channel can be inserted (injected) into a running sequence without disturbing this sequence. This is called Channel Injection Mode.

The Peripheral Event Controller (PEC) may be used to automatically store the conversion results into a table in memory for later evaluation, without requiring the overhead of entering and exiting interrupt routines for each data transfer.

After each reset and also during normal operation the ADC automatically performs calibration cycles. This automatic self-calibration constantly adjusts the converter to changing operating conditions (e.g. temperature) and compensates process variations.

These calibration cycles are part of the conversion cycle, so they do not affect the normal operation of the A/D converter.

In order to decouple analog inputs from digital noise and to avoid input trigger noise those pins used for analog input can be disconnected from the digital input stages under software control. This can be selected for each pin separately via register P5DIDIS (Port 5 Digital Input Disable).

The Auto-Power-Down feature of the A/D converter minimizes the power consumption when no conversion is in progress.

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3.9 Asynchronous/Synchronous Serial Interfaces (ASC0/ASC1)

The Asynchronous/Synchronous Serial Interfaces ASC0/ASC1 (USARTs) provide serial communication with other microcontrollers, processors, terminals or external peripheral components. They are upward compatible with the serial ports of the Infineon 8-bit microcontroller families and support full-duplex asynchronous communication and half-duplex synchronous communication. A dedicated baud rate generator with a fractional divider precisely generates all standard baud rates without oscillator tuning. For transmission, reception, error handling, and baudrate detection 5 separate interrupt vectors are provided.

In asynchronous mode, 8- or 9-bit data frames (with optional parity bit) are transmitted or received, preceded by a start bit and terminated by one or two stop bits. For multiprocessor communication, a mechanism to distinguish address from data bytes has been included (8-bit data plus wake-up bit mode). IrDA data transmissions up to 115.2 kbit/s with fixed or programmable IrDA pulse width are supported.

In synchronous mode, bytes (8 bits) are transmitted or received synchronously to a shift clock which is generated by the ASC0/1. The LSB is always shifted first.

In both modes, transmission and reception of data is FIFO-buffered. An autobaud detection unit allows to detect asynchronous data frames with its baudrate and mode with automatic initialization of the baudrate generator and the mode control bits.

A number of optional hardware error detection capabilities has been included to increase the reliability of data transfers. A parity bit can automatically be generated on transmission or be checked on reception. Framing error detection allows to recognize data frames with missing stop bits. An overrun error will be generated, if the last character received has not been read out of the receive buffer register at the time the reception of a new character is complete.

Summary of Features

- Full-duplex asynchronous operating modes
 - 8- or 9-bit data frames, LSB first, one or two stop bits, parity generation/checking
 - Baudrate from 2.5 Mbit/s to 0.6 bit/s (@ 40 MHz)
 - Multiprocessor mode for automatic address/data byte detection
 - Support for IrDA data transmission/reception up to max. 115.2 kbit/s (@ 40 MHz)
 - Auto baudrate detection
- Half-duplex 8-bit synchronous operating mode at 5 Mbit/s to 406.9 bit/s (@ 40 MHz)
- Buffered transmitter/receiver with FIFO support (8 entries per direction)
- Loop-back option available for testing purposes
- Interrupt generation on transmitter buffer empty condition, last bit transmitted condition, receive buffer full condition, error condition (frame, parity, overrun error), start and end of an autobaud detection

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3.10 High Speed Synchronous Serial Channels (SSC0/SSC1)

The High Speed Synchronous Serial Channels SSC0/SSC1 support full-duplex and half-duplex synchronous communication. It may be configured so it interfaces with serially linked peripheral components, full SPI functionality is supported.

A dedicated baud rate generator allows to set up all standard baud rates without oscillator tuning. For transmission, reception and error handling three separate interrupt vectors are provided.

The SSC transmits or receives characters of 2 ... 16 bits length synchronously to a shift clock which can be generated by the SSC (master mode) or by an external master (slave mode). The SSC can start shifting with the LSB or with the MSB and allows the selection of shifting and latching clock edges as well as the clock polarity.

A number of optional hardware error detection capabilities has been included to increase the reliability of data transfers. Transmit error and receive error supervise the correct handling of the data buffer. Phase error and baudrate error detect incorrect serial data.

Summary of Features

- Master or Slave mode operation
- Full-duplex or Half-duplex transfers
- Baudrate generation from 20 Mbit/s to 305.18 bit/s (@ 40 MHz)
- Flexible data format
 - Programmable number of data bits: 2 to 16 bits
 - Programmable shift direction: LSB-first or MSB-first
 - Programmable clock polarity: idle low or idle high
 - Programmable clock/data phase: data shift with leading or trailing clock edge
- Loop back option available for testing purposes
- Interrupt generation on transmitter buffer empty condition, receive buffer full condition, error condition (receive, phase, baudrate, transmit error)
- Three pin interface with flexible SSC pin configuration

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3.11 TwinCAN Module

The integrated TwinCAN module handles the completely autonomous transmission and reception of CAN frames in accordance with the CAN specification V2.0 part B (active), i.e. the on-chip TwinCAN module can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers.

Two Full-CAN nodes share the TwinCAN module's resources to optimize the CAN bus traffic handling and to minimize the CPU load. The module provides up to 32 message objects, which can be assigned to one of the CAN nodes and can be combined to FIFO-structures. Each object provides separate masks for acceptance filtering.

The flexible combination of Full-CAN functionality and FIFO architecture reduces the efforts to fulfill the real-time requirements of complex embedded control applications. Improved CAN bus monitoring functionality as well as the number of message objects permit precise and comfortable CAN bus traffic handling.

Gateway functionality allows automatic data exchange between two separate CAN bus systems, which reduces CPU load and improves the real time behavior of the entire system.

The bit timing for both CAN nodes is derived from the master clock and is programmable up to a data rate of 1 Mbit/s. Each CAN node uses two pins of Port 9 to interface to an external bus transceiver. The interface pins are assigned via software.

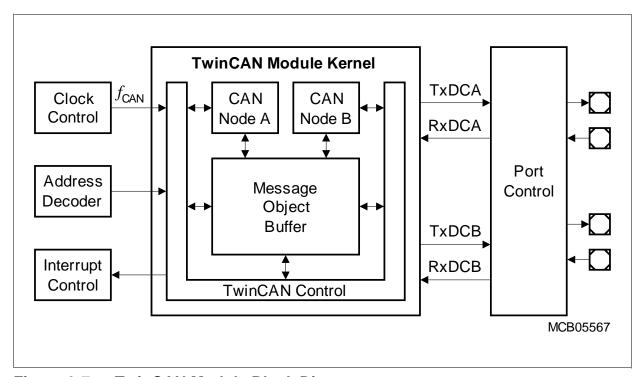


Figure 3-7 TwinCAN Module Block Diagram



Summary of Features

- CAN functionality according to CAN specification V2.0 B active
- Data transfer rate up to 1 Mbit/s
- Flexible and powerful message transfer control and error handling capabilities
- Full-CAN functionality and Basic CAN functionality for each message object
- 32 flexible message objects
 - Assignment to one of the two CAN nodes
 - Configuration as transmit object or receive object
 - Concatenation to a 2-, 4-, 8-, 16-, or 32-message buffer with FIFO algorithm
 - Handling of frames with 11-bit or 29-bit identifiers
 - Individual programmable acceptance mask register for filtering for each object
 - Monitoring via a frame counter
 - Configuration for Remote Monitoring Mode
- Up to eight individually programmable interrupt nodes can be used
- CAN Analyzer Mode for bus monitoring is implemented

3.12 LXBus Controller (EBC)

The EBC only controls accesses to resources connected to the on-chip LXBus. The LXBus is an internal representation of the external bus and allows accessing integrated peripherals and modules in the same way as external components.

The TwinCAN module is connected and accessed via the LXBus.

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3.13 Watchdog Timer

The Watchdog Timer represents one of the fail-safe mechanisms which have been implemented to prevent the controller from malfunctioning for longer periods of time.

The Watchdog Timer is always enabled after a reset of the chip, and can be disabled until the EINIT instruction has been executed (compatible mode), or it can be disabled and enabled at any time by executing instructions DISWDT and ENWDT (enhanced mode). Thus, the chip's start-up procedure is always monitored. The software has to be designed to restart the Watchdog Timer before it overflows. If, due to hardware or software related failures, the software fails to do so, the Watchdog Timer overflows and generates an internal hardware reset.

The Watchdog Timer is a 16-bit timer, clocked with the system clock divided by 2/4/128/256. The high byte of the Watchdog Timer register can be set to a prespecified reload value (stored in WDTREL) in order to allow further variation of the monitored time interval. Each time it is serviced by the application software, the high byte of the Watchdog Timer is reloaded and the low byte is cleared. Thus, time intervals between 13 µs and 419 ms can be monitored (@ 40 MHz).

The default Watchdog Timer interval after reset is 3.28 ms (@ 40 MHz).

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3.14 Clock Generation

The Clock Generation Unit uses a programmable on-chip PLL with multiple prescalers to generate the clock signals for the XC164GM with high flexibility. The master clock $f_{\rm MC}$ is the reference clock signal, and is used for TwinCAN and is output to the external system. The CPU clock $f_{\rm CPU}$ and the system clock $f_{\rm SYS}$ are derived from the master clock either directly (1:1) or via a 2:1 prescaler ($f_{\rm SYS} = f_{\rm CPU} = f_{\rm MC}$ / 2). See also Section 4.4.1.

The on-chip oscillator can drive an external crystal or accepts an external clock signal. The oscillator clock frequency can be multiplied by the on-chip PLL (by a programmable factor) or can be divided by a programmable prescaler factor.

If the bypass mode is used (direct drive or prescaler) the PLL can deliver an independent clock to monitor the clock signal generated by the on-chip oscillator. This PLL clock is independent from the XTAL1 clock. When the expected oscillator clock transitions are missing the Oscillator Watchdog (OWD) activates the PLL Unlock/OWD interrupt node and supplies the CPU with an emergency clock, the PLL clock signal. Under these circumstances the PLL will oscillate with its basic frequency.

The oscillator watchdog can be disabled by switching the PLL off. This reduces power consumption, but also no interrupt request will be generated in case of a missing oscillator clock.

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3.15 Parallel Ports

The XC164GM provides up to 47 I/O lines which are organized into three input/output ports and one input port. All port lines are bit-addressable, and all input/output lines are individually (bit-wise) programmable as inputs or outputs via direction registers. The I/O ports are true bidirectional ports which are switched to high impedance state when configured as inputs. The output drivers of some I/O ports can be configured (pin by pin) for push/pull operation or open-drain operation via control registers. During the internal reset, all port pins are configured as inputs.

The edge characteristics (shape) and driver characteristics (output current) of the port drivers can be selected via registers POCONx.

The input threshold of some ports is selectable (TTL or CMOS like), where the special CMOS like input threshold reduces noise sensitivity due to the input hysteresis. The input threshold may be selected individually for each byte of the respective ports.

Many port lines have programmable alternate input or output functions associated with them. All port lines that are not used for these alternate functions may be used as general purpose IO lines.

Table 3-5 Summary of the XC164GM's Parallel Ports

Port	Control	Alternate Functions
PORT1	Pad drivers	Serial interface lines
Port 3	Pad drivers, Open drain, Input threshold	Timer control signals, serial interface lines, System clock output CLKOUT (or FOUT)
Port 5	_	Analog input channels to the A/D converter, Timer control signals
Port 9	Pad drivers, Open drain, Input threshold	Capture inputs or compare outputs CAN interface lines ¹⁾

¹⁾ Can be assigned by software.

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3.16 Power Management

The XC164GM provides several means to control the power it consumes either at a given time or averaged over a certain timespan. Three mechanisms can be used (partly in parallel):

- **Power Saving Modes** switch the XC164GM into a special operating mode (control via instructions).
 - Idle Mode stops the CPU while the peripherals can continue to operate. Sleep Mode and Power Down Mode stop all clock signals and all operation (RTC may optionally continue running). Sleep Mode can be terminated by external interrupt signals.
- Clock Generation Management controls the distribution and the frequency of internal and external clock signals. While the clock signals for currently inactive parts of logic are disabled automatically, the user can reduce the XC164GM's CPU clock frequency which drastically reduces the consumed power.
 - External circuitry can be controlled via the programmable frequency output FOUT.
- **Peripheral Management** permits temporary disabling of peripheral modules (control via register SYSCON3). Each peripheral can separately be disabled/enabled.

The on-chip RTC supports intermittent operation of the XC164GM by generating cyclic wake-up signals. This offers full performance to quickly react on action requests while the intermittent sleep phases greatly reduce the average power consumption of the system.

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3.17 Instruction Set Summary

Table 3-6 lists the instructions of the XC164GM in a condensed way.

The various addressing modes that can be used with a specific instruction, the operation of the instructions, parameters for conditional execution of instructions, and the opcodes for each instruction can be found in the "Instruction Set Manual".

This document also provides a detailed description of each instruction.

Table 3-6 Instruction Set Summary

Mnemonic	Description	Bytes
ADD(B)	Add word (byte) operands	2/4
ADDC(B)	Add word (byte) operands with Carry	2/4
SUB(B)	Subtract word (byte) operands	2/4
SUBC(B)	Subtract word (byte) operands with Carry	2/4
MUL(U)	(Un)Signed multiply direct GPR by direct GPR (16- \times 16-bit)	2
DIV(U)	(Un)Signed divide register MDL by direct GPR (16-/16-bit)	2
DIVL(U)	(Un)Signed long divide reg. MD by direct GPR (32-/16-bit)	2
CPL(B)	Complement direct word (byte) GPR	2
NEG(B)	Negate direct word (byte) GPR	2
AND(B)	ND(B) Bitwise AND, (word/byte operands)	
(X)OR(B)	Bitwise (exclusive) OR, (word/byte operands)	2/4
BCLR/BSET	Clear/Set direct bit	2
BMOV(N)	Move (negated) direct bit to direct bit	4
BAND/BOR/BXOR	AND/OR/XOR direct bit with direct bit	4
BCMP	Compare direct bit to direct bit	4
BFLDH/BFLDL	Bitwise modify masked high/low byte of bit-addressable direct word memory with immediate data	4
CMP(B)	Compare word (byte) operands	2/4
CMPD1/2	Compare word data to GPR and decrement GPR by 1/2	2/4
CMPI1/2	Compare word data to GPR and increment GPR by 1/2	2/4
PRIOR	Determine number of shift cycles to normalize direct word GPR and store result in direct word GPR	2
SHL/SHR	Shift left/right direct word GPR	2
ROL/ROR	Rotate left/right direct word GPR	2



Table 3-6 Instruction Set Summary (cont'd)

Mnemonic	Description	Bytes		
ASHR	Arithmetic (sign bit) shift right direct word GPR	2		
MOV(B)	Move word (byte) data	2/4		
MOVBS/Z	Move byte operand to word op. with sign/zero extension	2/4		
JMPA/I/R	Jump absolute/indirect/relative if condition is met	4		
JMPS	Jump absolute to a code segment	4		
JB(C)	Jump relative if direct bit is set (and clear bit)	4		
JNB(S)	Jump relative if direct bit is not set (and set bit)	4		
CALLA/I/R	Call absolute/indirect/relative subroutine if condition is met	4		
CALLS	Call absolute subroutine in any code segment	4		
PCALL	Push direct word register onto system stack and call absolute subroutine	4		
TRAP	Call interrupt service routine via immediate trap number	2		
PUSH/POP	Push/pop direct word register onto/from system stack			
SCXT	Push direct word register onto system stack and update register with word operand	4		
RET(P)	Return from intra-segment subroutine (and pop direct word register from system stack)	2		
RETS	Return from inter-segment subroutine	2		
RETI	Return from interrupt service subroutine	2		
SBRK	Software Break	2		
SRST	Software Reset	4		
IDLE	Enter Idle Mode	4		
PWRDN	Enter Power Down Mode (supposes NMI-pin being low)	4		
SRVWDT	Service Watchdog Timer	4		
DISWDT/ENWDT	Disable/Enable Watchdog Timer	4		
EINIT	End-of-Initialization Register Lock	4		
ATOMIC	Begin ATOMIC sequence	2		
EXTR	Begin EXTended Register sequence	2		
EXTP(R)	Begin EXTended Page (and Register) sequence	2/4		
EXTS(R)	Begin EXTended Segment (and Register) sequence	2/4		
NOP	Null operation	2		



Table 3-6 Instruction Set Summary (cont'd)

Mnemonic	Description	Bytes
CoMUL/CoMAC	Multiply (and accumulate)	4
CoADD/CoSUB	Add/Subtract	4
Co(A)SHR/CoSHL	(Arithmetic) Shift right/Shift left	4
CoLOAD/STORE	Load accumulator/Store MAC register	4
CoCMP/MAX/MIN	Compare (maximum/minimum)	4
CoABS/CoRND	Absolute value/Round accumulator	4
CoMOV/NEG/NOP	Data move/Negate accumulator/Null operation	4



4 Electrical Parameters

4.1 General Parameters

Table 4-1 Absolute Maximum Ratings

Parameter	Symbol	Limit	Values	Unit	Notes
		Min.	Max.		
Storage temperature	T_{ST}	-65	150	°C	_
Junction temperature	T_{J}	-40	150	°C	Under bias
Voltage on $V_{\rm DDI}$ pins with respect to ground $(V_{\rm SS})$	V_{DDI}	-0.5	3.25	V	_
Voltage on $V_{\rm DDP}$ pins with respect to ground ($V_{\rm SS}$)	V_{DDP}	-0.5	6.2	V	_
Voltage on any pin with respect to ground $(V_{\rm SS})$	V_{IN}	-0.5	V _{DDP} + 0.5	V	_
Input current on any pin during overload condition	_	-10	10	mA	_
Absolute sum of all input currents during overload condition	_	_	100	mA	_

Note: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. During absolute maximum rating overload conditions $(V_{IN} > V_{DDP})$ or $V_{IN} < V_{SS}$ the voltage on V_{DDP} pins with respect to ground (V_{SS}) must not exceed the values defined by the absolute maximum ratings.



Operating Conditions

The following operating conditions must not be exceeded to ensure correct operation of the XC164GM. All parameters specified in the following sections refer to these operating conditions, unless otherwise noticed.

Table 4-2 Operating Condition Parameters

Parameter	Symbol	Lim	it Values	Unit	Notes
		Min.	Max.		
Digital supply voltage for the core	V_{DDI}	2.35	2.7	V	Active mode, $f_{\text{CPU}} = f_{\text{CPUmax}}^{1)}$
Digital supply voltage for IO pads	V_{DDP}	4.4	5.5	V	Active mode ²⁾³⁾
Supply Voltage Difference	ΔV_{DD}	-0.5	_	V	V_{DDP} - $V_{DDI}^{4)}$
Digital ground voltage	V_{SS}	0	'	V	Reference voltage
Overload current	I_{OV}	-5	5	mA	Per IO pin ⁵⁾⁶⁾
		-2	5	mA	Per analog input pin ⁵⁾⁶⁾
Overload current coupling	K_{OVA}	_	1.0 × 10 ⁻⁴	_	<i>I</i> _{OV} > 0
factor for analog inputs ⁷⁾		_	1.5×10^{-3}	_	<i>I</i> _{OV} < 0
Overload current coupling	K_{OVD}	_	5.0 × 10 ⁻³	_	<i>I</i> _{OV} > 0
factor for digital I/O pins ⁷⁾		_	1.0 × 10 ⁻²	_	<i>I</i> _{OV} < 0
Absolute sum of overload currents	$\Sigma I_{OV} $	_	50	mA	6)
External Load Capacitance	C_{L}	_	50	pF	Pin drivers in default mode ⁸⁾
Ambient temperature	T_{A}	0	70	°C	SAB-XC164
		-40	85	°C	SAF-XC164
		-40	125	°C	SAK-XC164

¹⁾ $f_{\text{CPUmax}} = 40 \text{ MHz}$ for devices marked ... 40F, $f_{\text{CPUmax}} = 20 \text{ MHz}$ for devices marked ... 20F.

²⁾ External circuitry must guarantee low-level at the RSTIN pin at least until both power supply voltages have reached the operating range.

³⁾ The specified voltage range is allowed for operation. The range limits may be reached under extreme operating conditions. However, specified parameters, such as leakage currents, refer to the standard operating voltage range of $V_{\rm DDP} = 4.75$ V to 5.25 V.

⁴⁾ This limitation must be fulfilled under all operating conditions including power-ramp-up, power-ramp-down, and power-save modes.



- 5) Overload conditions occur if the standard operating conditions are exceeded, i.e. the voltage on any pin exceeds the specified range: V_{OV} > V_{DDP} + 0.5 V (I_{OV} > 0) or V_{OV} < V_{SS} 0.5 V (I_{OV} < 0). The absolute sum of input overload currents on all pins may not exceed **50 mA**. The supply voltages must remain within the specified limits.
 - Proper operation is not guaranteed if overload conditions occur on functional pins such as XTAL1.
- 6) Not subject to production test verified by design/characterization.
- 7) An overload current (I_{OV}) through a pin injects a certain error current (I_{INJ}) into the adjacent pins. This error current adds to the respective pin's leakage current (I_{OZ}) . The amount of error current depends on the overload current and is defined by the overload coupling factor K_{OV} . The polarity of the injected error current is inverse compared to the polarity of the overload current that produces it.
 - The total current through a pin is $|I_{TOT}| = |I_{OZ}| + (|I_{OV}| \times K_{OV})$. The additional error current may distort the input voltage on analog inputs.
- 8) The timing is valid for pin drivers operating in default current mode (selected after reset). Reducing the output current may lead to increased delays or reduced driving capability (C_1) .

Parameter Interpretation

The parameters listed in the following partly represent the characteristics of the XC164GM and partly its demands on the system. To aid in interpreting the parameters right, when evaluating them for a design, they are marked in column "Symbol":

CC (Controller Characteristics):

The logic of the XC164GM will provide signals with the respective characteristics.

SR (System Requirement):

The external system must provide signals with the respective characteristics to the XC164GM.

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4.2 DC Parameters

Table 4-3 DC Characteristics (Operating Conditions apply)¹⁾

Parameter	Symbol		Limit Values		Unit	Test Condition	
			Min.	Max.	1		
Input low voltage TTL (all except XTAL1)	V_{IL}	SR	-0.5	$\begin{array}{c} 0.2 \times V_{\rm DDP} \\ \text{-} \ 0.1 \end{array}$	V	_	
Input low voltage XTAL1	V_{ILC}	SR	-0.5	$0.3 imes V_{ m DDI}$	V	_	
Input low voltage (Special Threshold)	V_{ILS}	SR	-0.5	$0.45 imes V_{ m DDP}$	V	2)	
Input high voltage TTL (all except XTAL1)	V_{IH}	SR	$\begin{array}{c} 0.2 \times V_{\rm DDP} \\ + 0.9 \end{array}$	V _{DDP} + 0.5	V	-	
Input high voltage XTAL1	V_{IHC}	SR	$0.7 imes V_{ m DDI}$	V _{DDI} + 0.5	V	-	
Input high voltage (Special Threshold)	V_{IHS}	SR	$\begin{array}{c} 0.8 \times V_{\rm DDP} \\ \text{-} \ 0.2 \end{array}$	V _{DDP} + 0.5	V	2)	
Input Hysteresis (Special Threshold)	HYS		$0.04 imes V_{ extsf{DDP}}$	-	V	$V_{\rm DDP}$ in [V], Series resistance = 0 Ω^{2}	
Output low voltage	V_{OL}	CC	_	1.0	V	$I_{\rm OL} \leq I_{\rm OLmax}^{3)}$	
			_	0.45	V	$I_{\rm OL} \le I_{\rm OLnom}^{3)4)}$	
Output high voltage ⁵⁾	V_{OH}	CC	V_{DDP} - 1.0	_	V	$I_{\text{OH}} \ge I_{\text{OHmax}}^{3)}$	
			V _{DDP} - 0.45	_	V	$I_{\text{OH}} \ge I_{\text{OHnom}}^{3)4)}$	
Input leakage current (Port 5) ⁶⁾	I_{OZ1}	CC	_	±300	nA	$0 \text{ V} < V_{\text{IN}} < V_{\text{DDP}},$ $T_{\text{A}} \leq 125 \text{ °C}$	
				±200	nA	$0 \text{ V} < V_{\text{IN}} < V_{\text{DDP}},$ $T_{\text{A}} \le 85 {}^{\circ}\text{C}^{11)}$	
Input leakage current (all other ⁷⁾) ⁶⁾	$I_{\rm OZ2}$	СС	_	±500	nA	$\begin{array}{c} 0.45 \; \mathrm{V} < V_{\mathrm{IN}} < \\ V_{\mathrm{DDP}} \end{array}$	
Configuration pull-up	$I_{CPUH}^{9)}$		_	-10	μΑ	$V_{IN} = V_{IHmin}$	
current ⁸⁾	$I_{\text{CPUL}}^{10)}$		-100	_	μΑ	$V_{IN} = V_{ILmax}$	



Table 4-3 DC Characteristics (Operating Conditions apply)¹⁾ (cont'd)

Parameter	Symbol		Limit	Values	Unit	Test Condition
			Min.	Max.		
XTAL1 input current	I_{IL}	CC	_	±20	μΑ	$0 \; V < V_{IN} < V_{DDI}$
Pin capacitance ¹¹⁾ (digital inputs/outputs)	C_{IO}	CC	_	10	pF	-

- 1) Keeping signal levels within the limits specified in this table, ensures operation without overload conditions. For signal levels outside these specifications, also refer to the specification of the overload current I_{OV} .
- 2) This parameter is tested for P3, P9.
- 3) The maximum deliverable output current of a port driver depends on the selected output driver mode, see Table 4-4, Current Limits for Port Output Drivers. The limit for pin groups must be respected.
- 4) As a rule, with decreasing output current the output levels approach the respective supply level ($V_{\rm OL} \to V_{\rm SS}$, $V_{\rm OH} \to V_{\rm DDP}$). However, only the levels for nominal output currents are guaranteed.
- 5) This specification is not valid for outputs which are switched to open drain mode. In this case the respective output will float and the voltage results from the external circuitry.
- 6) An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin. Please refer to the definition of the overload coupling factor K_{OV} .
- 7) The driver of P3.15 is designed for faster switching, because this pin can deliver the system clock (CLKOUT). The maximum leakage current for P3.15 is, therefore, increased to 1µA.
- 8) During a hardware reset this specification is valid for configuration on P1H.4, P1H.5, P9.4 and P9.5. After a hardware reset this specification is valid for NMI.
- 9) The maximum current may be drawn while the respective signal line remains inactive.
- 10) The minimum current must be drawn to drive the respective signal line active.
- 11) Not subject to production test verified by design/characterization.

Table 4-4 Current Limits for Port Output Drivers

Port Output Driver Mode	Maximum Output Current $(I_{OLmax}, -I_{OHmax})^{1}$	Nominal Output Current $(I_{OLnom}, -I_{OHnom})$
Strong driver	10 mA	2.5 mA
Medium driver	4.0 mA	1.0 mA
Weak driver	0.5 mA	0.1 mA

¹⁾ An output current above $|I_{\text{OXnom}}|$ may be drawn from up to three pins at the same time. For any group of 16 neighboring port output pins the total output current in each direction (ΣI_{OL} and Σ - I_{OH}) must remain below 50 mA.

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Table 4-5 Power Consumption XC164GM (Operating Conditions apply)

Parameter	Sym-	Limit Values		Unit	Test Condition
	bol	Min.	Max.		
Power supply current (active) with all peripherals active	I_{DDI}	_	10 + $2.6 \times f_{\text{CPU}}$	mA	f_{CPU} in $[MHz]^{1)2)}$
Pad supply current	I_{DDP}	_	5	mA	3)
Idle mode supply current with all peripherals active	I_{IDX}	_	$10 + 1.2 \times f_{\text{CPU}}$	mA	f_{CPU} in [MHz] $^{2)}$
Sleep and Power down mode supply current caused by leakage ⁴⁾	$I_{PDL}^{5)}$	-	128,000 × e ^{-α}	mA	$V_{\rm DDI} = V_{\rm DDImax}^{6)}$ $T_{\rm J}$ in [°C] $\alpha = 4670 / (273 + T_{\rm J})$
Sleep and Power down mode supply current caused by leakage and the RTC running, clocked by the main oscillator ⁴⁾	$I_{PDM}^{7)}$	_	$\begin{array}{c} 0.6 + \\ 0.02 \times f_{\rm OSC} \\ + I_{\rm PDL} \end{array}$	mA	$\begin{aligned} V_{\rm DDI} &= V_{\rm DDImax} \\ f_{\rm OSC} &\text{in [MHz]} \end{aligned}$

- 1) During Flash programming or erase operations the supply current is increased by max. 5 mA.
- 2) The supply current is a function of the operating frequency. This dependency is illustrated in **Figure 4-1**. These parameters are tested at $V_{\rm DDImax}$ and maximum CPU clock frequency with all outputs disconnected and all inputs at $V_{\rm IL}$ or $V_{\rm IH}$.
- 3) The pad supply voltage pins ($V_{\rm DDP}$) mainly provides the current consumed by the pin output drivers. A small amount of current is consumed even though no outputs are driven, because the drivers' input stages are switched and also the Flash module draws some power from the $V_{\rm DDP}$ supply.
- 4) The total supply current in Sleep and Power down mode is the sum of the temperature dependent leakage current and the frequency dependent current for RTC and main oscillator.
- 5) This parameter is determined mainly by the transistor leakage currents. This current heavily depends on the junction temperature (see **Figure 4-3**). The junction temperature T_J is the same as the ambient temperature T_A if no current flows through the port output drivers. Otherwise, the resulting temperature difference must be taken into account.
- 6) All inputs (including pins configured as inputs) at 0 V to 0.1 V or at $V_{\rm DDP}$ 0.1 V to $V_{\rm DDP}$, all outputs (including pins configured as outputs) disconnected. This parameter is tested at 25 °C and is valid for $T_{\rm J} \ge$ 25 °C.
- 7) This parameter is determined mainly by the current consumed by the oscillator switched to low gain mode (see Figure 4-2). This current, however, is influenced by the external oscillator circuitry (crystal, capacitors). The given values refer to a typical circuitry and may change in case of a not optimized external oscillator circuitry.



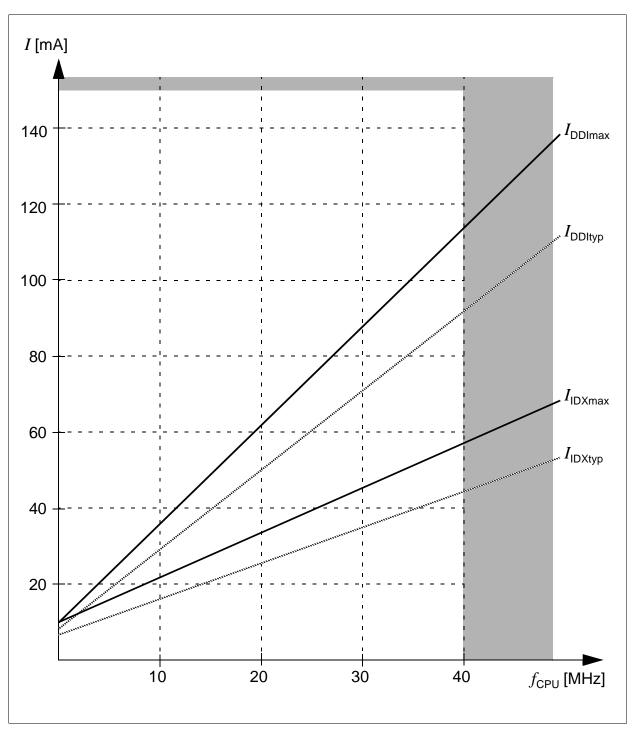


Figure 4-1 Supply/Idle Current as a Function of Operating Frequency



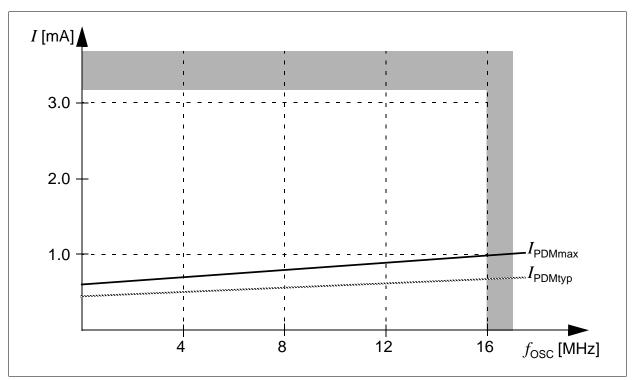


Figure 4-2 Sleep and Power Down Supply Current due to RTC and Oscillator Running, as a Function of Oscillator Frequency

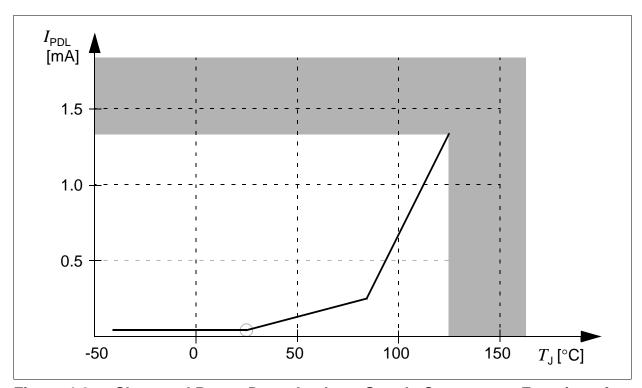


Figure 4-3 Sleep and Power Down Leakage Supply Current as a Function of Temperature



4.3 Analog/Digital Converter Parameters

Table 4-6 A/D Converter Characteristics (Operating Conditions apply)

Symbol		Limit Values Min. Max.		Unit	Test Condition
V_{AREF}	SR	4.5	V _{DDP} + 0.1	V	1)
V_{AGND}	SR	V _{SS} - 0.1	$V_{\rm SS}$ + 0.1	V	_
V_{AIN}	SR	V_{AGND}	V_{AREF}	V	2)
f_{BC}		0.5	20	MHz	3)
t _{C10P}	CC	52 × t _{BC} +	$t_{\rm S}$ + 6 × $t_{\rm SYS}$	_	Post-calibr. o
t _{C10}	CC	40 × t _{BC} +	$t_{\rm S}$ + 6 × $t_{\rm SYS}$	_	Post-calibr. o
t _{C8P}	CC	$44 \times t_{BC}$ +	$t_{\rm S}$ + 6 × $t_{\rm SYS}$	_	Post-calibr. o
t _{C8}	CC	$32 \times t_{BC} + t_{S} + 6 \times t_{SYS}$		_	Post-calibr. o
t_{CAL}	CC	484	11,696	t_{BC}	5)
TUE	CC	_	±2	LSB	1)
C_{AINT}	СС	_	15	pF	6)
C_{AINS}	СС	_	10	pF	6)
R_{AIN}	СС	_	2	kΩ	6)
C_{AREFT}	СС	_	20	pF	6)
C_{AREFS}	СС	_	15	pF	6)
R_{AREF}	СС	_	1	kΩ	6)
	V_{AREF} V_{AGND} V_{AIN} f_{BC} t_{C10P} t_{C30P} t_{C8} t_{CAL} TUE C_{AINT} C_{AREFT} C_{AREFS}	$V_{ m AREF}$ SR $V_{ m AGND}$ SR $V_{ m AIN}$ SR $f_{ m BC}$ CC $t_{ m C10P}$ CC $t_{ m C8P}$ CC $t_{ m C8}$ CC $t_{ m CAL}$ CC TUE CC $C_{ m AINT}$ CC $C_{ m AINS}$ CC $C_{ m AREFT}$ CC	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$\begin{array}{ c c c c }\hline & Min. & Max. \\ \hline V_{AREF} & SR & 4.5 & V_{DDP} \\ V_{AGND} & SR & V_{SS} - 0.1 & V_{SS} + 0.1 \\ \hline V_{AIN} & SR & V_{AGND} & V_{AREF} \\ \hline f_{BC} & 0.5 & 20 \\ \hline t_{C10P} & CC & 52 \times t_{BC} + t_{S} + 6 \times t_{SYS} \\ \hline t_{C10} & CC & 40 \times t_{BC} + t_{S} + 6 \times t_{SYS} \\ \hline t_{C8P} & CC & 44 \times t_{BC} + t_{S} + 6 \times t_{SYS} \\ \hline t_{C8} & CC & 32 \times t_{BC} + t_{S} + 6 \times t_{SYS} \\ \hline t_{CAL} & CC & 484 & 11,696 \\ \hline TUE & CC & - & \pm 2 \\ \hline C_{AINT} & CC & - & 15 \\ \hline C_{AINS} & CC & - & 20 \\ \hline C_{AREFT} & CC & - & 20 \\ \hline C_{AREFS} & CC & - & 15 \\ \hline \end{array}$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$

¹⁾ TUE is tested at $V_{\text{AREF}} = V_{\text{DDP}} + 0.1 \text{ V}$, $V_{\text{AGND}} = 0 \text{ V}$. It is verified by design for all other voltages within the defined voltage range.

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If the analog reference supply voltage drops below 4.5 V (i.e. $V_{\text{AREF}} \ge 4.0 \text{ V}$) or exceeds the power supply voltage by up to 0.2 V (i.e. $V_{\text{AREF}} = V_{\text{DDP}} + 0.2 \text{ V}$) the maximum TUE is increased to ± 3 LSB. This range is not subject to production test.

The specified TUE is guaranteed only, if the absolute sum of input overload currents on Port 5 pins (see $I_{\rm OV}$ specification) does not exceed 10 mA, and if $V_{\rm AREF}$ and $V_{\rm AGND}$ remain stable during the respective period of time. During the reset calibration sequence the maximum TUE may be ± 4 LSB.



- 2) $V_{\rm AIN}$ may exceed $V_{\rm AGND}$ or $V_{\rm AREF}$ up to the absolute maximum ratings. However, the conversion result in these cases will be X000_H or X3FF_H, respectively.
- 3) The limit values for $f_{\rm BC}$ must not be exceeded when selecting the peripheral frequency and the ADCTC setting.
- 4) This parameter includes the sample time t_S, the time for determining the digital result and the time to load the result register with the conversion result (t_{SYS} = 1/f_{SYS}).
 Values for the basic clock t_{BC} depend on programming and can be taken from Table 4-7.
 - When the post-calibration is switched off, the conversion time is reduced by 12 x $t_{\rm BC}$.
- 5) The actual duration of the reset calibration depends on the noise on the reference signal. Conversions executed during the reset calibration increase the calibration time. The TUE for those conversions may be increased.
- 6) Not subject to production test verified by design/characterization. The given parameter values cover the complete operating range. Under relaxed operating conditions (temperature, supply voltage) reduced values can be used for calculations. At room temperature and nominal supply voltage the following typical values can be used: C_{AINTtyp} = 12 pF, C_{AINStyp} = 7 pF, R_{AINtyp} = 1.5 kΩ, C_{AREFTtyp} = 15 pF, C_{AREFStyp} = 13 pF, R_{AREFtyp} = 0.7 kΩ.

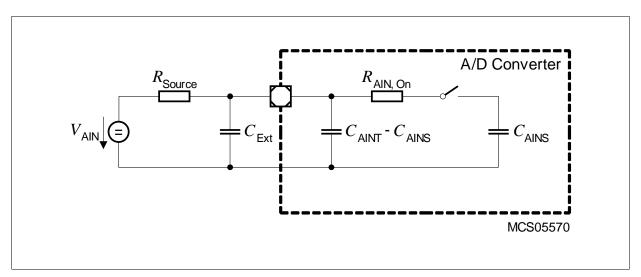


Figure 4-4 Equivalent Circuitry for Analog Inputs

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Sample time and conversion time of the XC164GM's A/D Converter are programmable. In compatibility mode, the above timing can be calculated using **Table 4-7**. The limit values for $f_{\rm BC}$ must not be exceeded when selecting ADCTC.

Table 4-7 A/D Converter Computation Table 1)

ADCON.15 14 (ADCTC)	A/D Converter Basic Clock $f_{\rm BC}$	ADCON.13 12 (ADSTC)	Sample Time t _S
00	f_{SYS} / 4	00	$t_{\rm BC} \times 8$
01	f_{SYS} / 2	01	$t_{\rm BC} \times 16$
10	f_{SYS} / 16	10	$t_{\rm BC} \times 32$
11	f _{SYS} / 8	11	$t_{\rm BC} \times 64$

¹⁾ These selections are available in compatibility mode. An improved mechanism to control the ADC input clock can be selected.

Converter Timing Example:

Assumptions:	f_{SYS}	= 40 MHz (i.e. t_{SYS} = 25 ns), ADCTC = '01', ADSTC = '00'					
Basic clock	f_{BC}	$= f_{SYS} / 2 = 20 \text{ MHz}, i.e. t_{BC} = 50 \text{ ns}$					
Sample time	t _S	$= t_{BC} \times 8 = 400 \text{ ns}$					
Conversion 10-bit:							
With post-calibr.	t _{C10P}	= $52 \times t_{BC} + t_{S} + 6 \times t_{SYS} = (2600 + 400 + 150) \text{ ns} = 3.15 \mu\text{s}$					
Post-calibr. off	t _{C10}	= $40 \times t_{BC} + t_{S} + 6 \times t_{SYS}$ = (2000 + 400 + 150) ns = 2.55 µs					
Conversion 8-bit:							
With post-calibr.	t _{C8P}	= $44 \times t_{BC} + t_{S} + 6 \times t_{SYS} = (2200 + 400 + 150) \text{ ns} = 2.75 \mu\text{s}$					
Post-calibr. off	t _{C8}	= $32 \times t_{BC} + t_{S} + 6 \times t_{SYS} = (1600 + 400 + 150) \text{ ns} = 2.15 \mu\text{s}$					

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4.4 AC Parameters

4.4.1 Definition of Internal Timing

The internal operation of the XC164GM is controlled by the internal master clock f_{MC} .

The master clock signal $f_{\rm MC}$ can be generated from the oscillator clock signal $f_{\rm OSC}$ via different mechanisms. The duration of master clock periods (TCMs) and their variation (and also the derived external timing) depend on the used mechanism to generate $f_{\rm MC}$. This influence must be regarded when calculating the timings for the XC164GM.

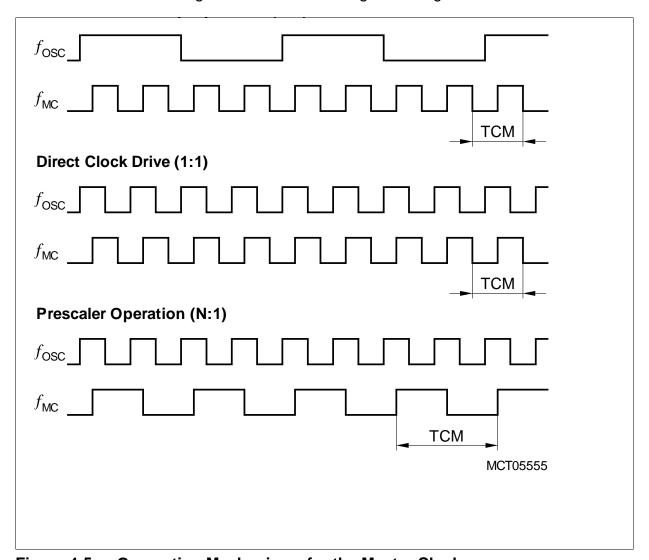


Figure 4-5 Generation Mechanisms for the Master Clock

Note: The example for PLL operation shown in **Figure 4-5** refers to a PLL factor of 1:4, the example for prescaler operation refers to a divider factor of 2:1.



The used mechanism to generate the master clock is selected by register PLLCON.

CPU and EBC are clocked with the CPU clock signal f_{CPU} . The CPU clock can have the same frequency as the master clock ($f_{CPU} = f_{MC}$) or can be the master clock divided by two: $f_{CPU} = f_{MC}$ / 2. This factor is selected by bit CPSYS in register SYSCON1.

The specification of the external timing (AC Characteristics) depends on the period of the CPU clock, called "TCP".

The other peripherals are supplied with the system clock signal f_{SYS} which has the same frequency as the CPU clock signal f_{CPU} .

Bypass Operation

When bypass operation is configured (PLLCTRL = $0x_B$) the master clock is derived from the internal oscillator (input clock signal XTAL1) through the input- and output-prescalers:

$$f_{MC} = f_{OSC} / ((PLLIDIV+1) \times (PLLODIV+1)).$$

If both divider factors are selected as '1' (PLLIDIV = PLLODIV = '0') the frequency of $f_{\rm MC}$ directly follows the frequency of $f_{\rm OSC}$ so the high and low time of $f_{\rm MC}$ is defined by the duty cycle of the input clock $f_{\rm OSC}$.

The lowest master clock frequency is achieved by selecting the maximum values for both divider factors:

$$f_{MC} = f_{OSC} / ((3 + 1) \times (14 + 1)) = f_{OSC} / 60.$$

Phase Locked Loop (PLL)

When PLL operation is configured (PLLCTRL = 11_B) the on-chip phase locked loop is enabled and provides the master clock. The PLL multiplies the input frequency by the factor \mathbf{F} ($f_{MC} = f_{OSC} \times \mathbf{F}$) which results from the input divider, the multiplication factor, and the output divider ($\mathbf{F} = \text{PLLMUL+1} / (\text{PLLIDIV+1} \times \text{PLLODIV+1})$). The PLL circuit synchronizes the master clock to the input clock. This synchronization is done smoothly, i.e. the master clock frequency does not change abruptly.

Due to this adaptation to the input clock the frequency of $f_{\rm MC}$ is constantly adjusted so it is locked to $f_{\rm OSC}$. The slight variation causes a jitter of $f_{\rm MC}$ which also affects the duration of individual TCMs.

The timing listed in the AC Characteristics refers to TCPs. Because $f_{\rm CPU}$ is derived from $f_{\rm MC}$, the timing must be calculated using the minimum TCP possible under the respective circumstances.

The actual minimum value for TCP depends on the jitter of the PLL. As the PLL is constantly adjusting its output frequency so it corresponds to the applied input frequency (crystal or oscillator) the relative deviation for periods of more than one TCP is lower than for one single TCP (see formula and Figure 4-6).

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This is especially important for bus cycles using waitstates and e.g. for the operation of timers, serial interfaces, etc. For all slower operations and longer periods (e.g. pulse train generation or measurement, lower baudrates, etc.) the deviation caused by the PLL jitter is negligible.

The value of the accumulated PLL jitter depends on the number of consecutive VCO output cycles within the respective timeframe. The VCO output clock is divided by the output prescaler (K = PLLODIV+1) to generate the master clock signal $f_{\rm MC}$. Therefore, the number of VCO cycles can be represented as K × **N**, where **N** is the number of consecutive $f_{\rm MC}$ cycles (TCM).

For a period of $\mathbf{N} \times \text{TCM}$ the accumulated PLL jitter is defined by the deviation D_N : D_N [ns] = $\pm (1.5 + 6.32 \times \mathbf{N} / f_{MC})$; f_{MC} in [MHz], \mathbf{N} = number of consecutive TCMs. So, for a period of 3 TCMs @ 20 MHz and K = 12: $D_3 = \pm (1.5 + 6.32 \times \mathbf{3} / 20) = 2.448$ ns. This formula is applicable for K $\times \mathbf{N}$ < 95. For longer periods the K $\times \mathbf{N}$ = 95 value can be used. This steady value can be approximated by: D_{Nmax} [ns] = $\pm (1.5 + 600 / (K \times f_{MC}))$.

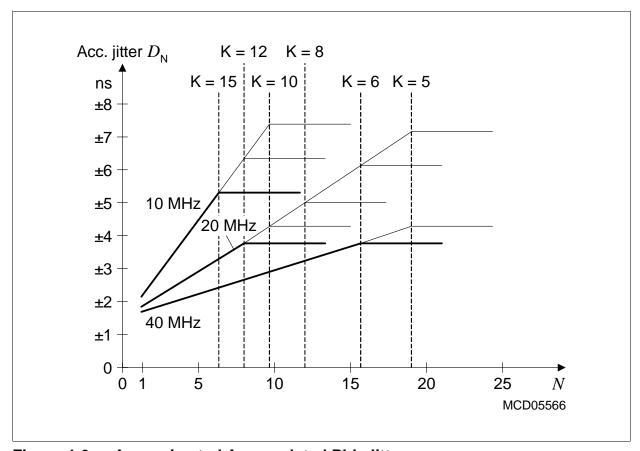


Figure 4-6 Approximated Accumulated PLL Jitter

Note: The bold lines indicate the minimum accumulated jitter which can be achieved by selecting the maximum possible output prescaler factor K.

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Different frequency bands can be selected for the VCO, so the operation of the PLL can be adjusted to a wide range of input and output frequencies:

Table 4-8 VCO Bands for PLL Operation¹⁾

PLLCON.PLLVB	VCO Frequency Range	Base Frequency Range
00	100 150 MHz	20 80 MHz
01	150 200 MHz	40 130 MHz
10	200 250 MHz	60 180 MHz
11	Reserved	

¹⁾ Not subject to production test - verified by design/characterization.



4.4.2 On-chip Flash Operation

The XC164GM's Flash module delivers data within a fixed access time (see **Table 4-9**).

Accesses to the Flash module are controlled by the PMI and take 1+WS clock cycles, where WS is the number of Flash access waitstates selected via bitfield WSFLASH in register IMBCTRL. The resulting duration of the access phase must cover the access time $t_{\rm ACC}$ of the Flash array. The required Flash waitstates depend on the actual system frequency.

Note: The Flash access waitstates only affect non-sequential accesses. Due to prefetching mechanisms, the performance for sequential accesses (depending on the software structure) is only partially influenced by waitstates.

In typical applications, eliminating one waitstate increases the average performance by 5% ... 15%.

Table 4-9 Flash Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values			Unit
			Min.	Тур.	Max.	
Flash module access time	t_{ACC}	CC	_	_	50 ¹⁾	ns
Programming time per 128-byte block	t_{PR}	CC	_	2 ²⁾	5	ms
Erase time per sector	$t_{\sf ER}$	CC	_	200 ²⁾	500	ms

¹⁾ The actual access time is influenced by the system frequency, see Table 4-10.

Example: For an operating frequency of 40 MHz (clock cycle = 25 ns), the Flash accesses must be executed with 1 waitstate: $((1+1) \times 25 \text{ ns}) \ge 50 \text{ ns}$.

Table 4-10 indicates the interrelation of waitstates and system frequency.

Table 4-10 Flash Access Waitstates

Required Waitstates	Frequency Range			
0 WS (WSFLASH = 00 _B)	$f_{\text{CPU}} \le 20 \text{ MHz}$			
1 WS (WSFLASH = 01 _B)	$f_{\text{CPU}} \le 40 \text{ MHz}$			

Note: The maximum achievable system frequency is limited by the properties of the respective derivative, i.e. 40 MHz (or 20 MHz for XC164GM-xF20F devices).

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²⁾ Programming and erase time depends on the system frequency. Typical values are valid for 40MHz.



4.4.3 External Clock Drive XTAL1

Table 4-11 External Clock Drive Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values		Unit
			Min.	Max.	
Oscillator period	$t_{ m OSC}$	SR	25	250 ¹⁾	ns
High time ²⁾	t ₁	SR	6	_	ns
Low time ²⁾	t_2	SR	6	_	ns
Rise time ²⁾	t_3	SR	_	8	ns
Fall time ²⁾	t_4	SR	_	8	ns

- 1) The maximum limit is only relevant for PLL operation to ensure the minimum input frequency for the PLL.
- 2) The clock input signal must reach the defined levels $V_{\rm II,C}$ and $V_{\rm IHC}$.

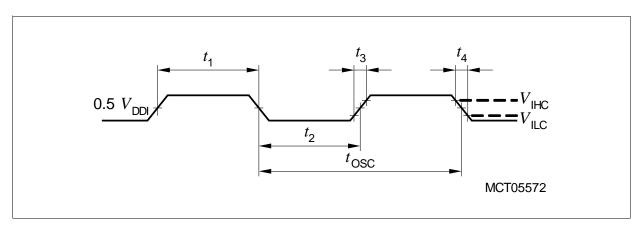


Figure 4-7 External Clock Drive XTAL1

Note: If the on-chip oscillator is used together with a crystal or a ceramic resonator, the oscillator frequency is limited to a range of 4 MHz to 16 MHz.

It is strongly recommended to measure the oscillation allowance (negative resistance) in the final target system (layout) to determine the optimum parameters for the oscillator operation. Please refer to the limits specified by the crystal supplier.

When driven by an external clock signal it will accept the specified frequency range. Operation at lower input frequencies is possible but is verified by design only (not subject to production test).



Package and Reliability

5 Package and Reliability

5.1 Packaging

Table 5-1 Package Parameters (PG-TQFP-64-8)

Parameter	Symbol	Lim	it Values	Unit	Notes	
		Min.	Max.			
Power dissipation	P_{DISS}	_	0.6	W	_	
Thermal resistance	R_{THA}	_	28	K/W	Chip-Ambient	

Package Outlines

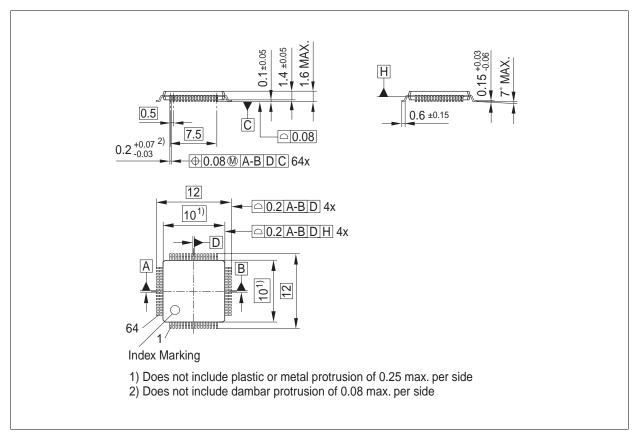


Figure 5-1 PG-TQFP-64-8 (Plastic Thin Quad Flat Package)

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Dimensions in mm.



Package and Reliability

5.2 Flash Memory Parameters

The data retention time of the XC164GM's Flash memory (i.e. the time after which stored data can still be retrieved) depends on the number of times the Flash memory has been erased and programmed.

Table 5-2 Flash Parameters (XC164GM, 32 or 64 Kbytes)

Parameter	Symbol	Limit Values		Unit	Notes
		Min.	Max.		
Data retention time	t_{RET}	15	_	years	Max. 10 ³ erase/program cycles
Flash Erase Endurance	N_{ER}	20 × 10 ³	_	_	Max. data retention time 5 years

5.3 Quality Declarations

Table 5-3 Quality Parameters

Parameter	Symbol	Limit Values		Unit	Notes
		Min.	Max.		
ESD susceptibility according to Human Body Model (HBM)	V_{HBM}	_	2000	V	Conforming to EIA/JESD22- A114-B
ESD susceptibility according to Socketed Device Model (SDM)	V_{SDM}	_	500	V	Conforming to ESDA Std DS5.3- 1993
Moisture Sensitivity Level (MSL)	_	_	3	-	Conforming to Jedec J-STD- 020C for 240 °C

Note: Information about soldering can be found on the "package" information page under: http://www.infineon.com/package

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